
MSGCROC - funkcjonalność układu

Wstępne testy

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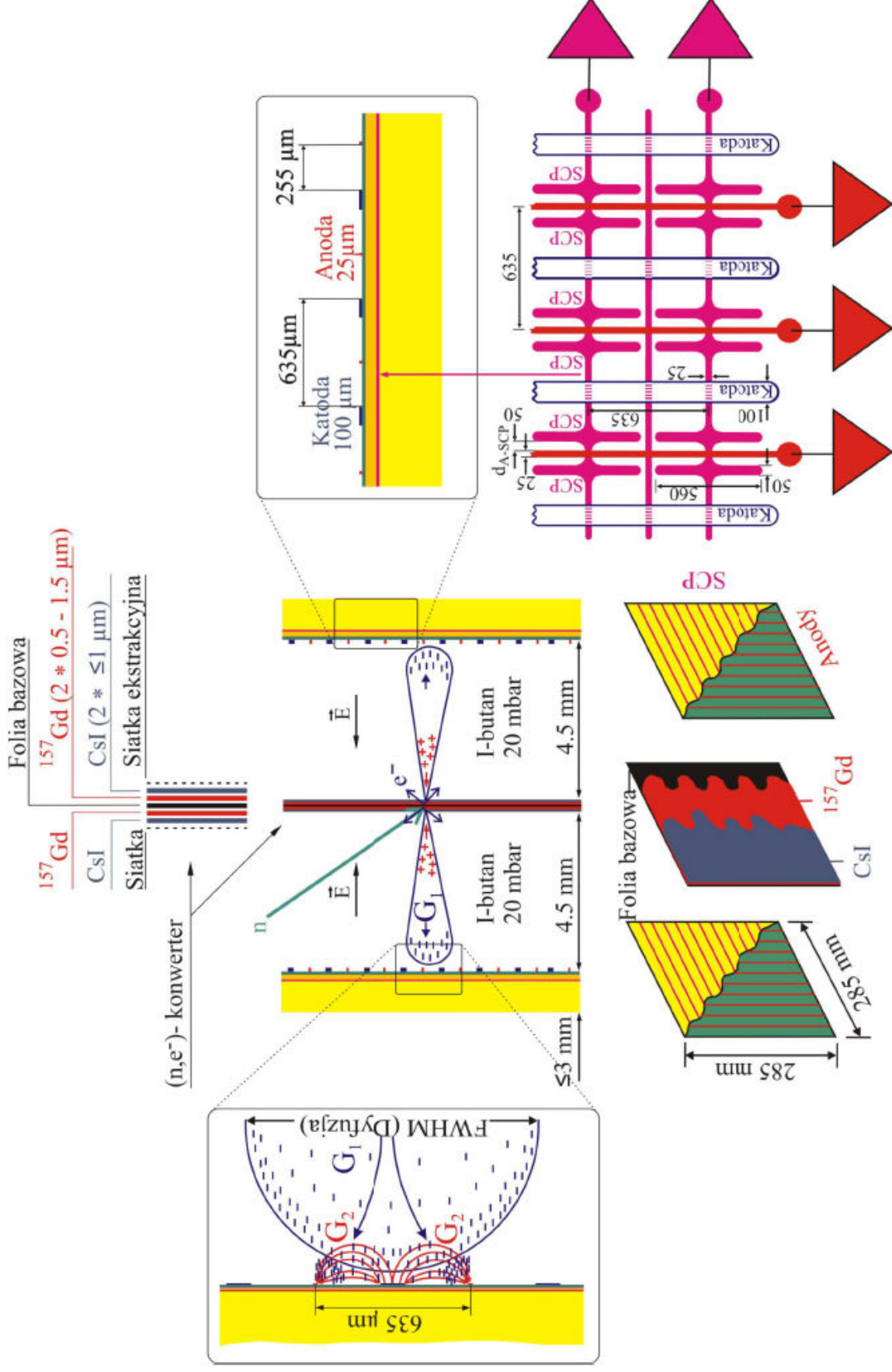
MSGCROC – Micro-Strip Gas Chamber ReadOut Chip

DETRI – DETectors for Neutron Instrumentation

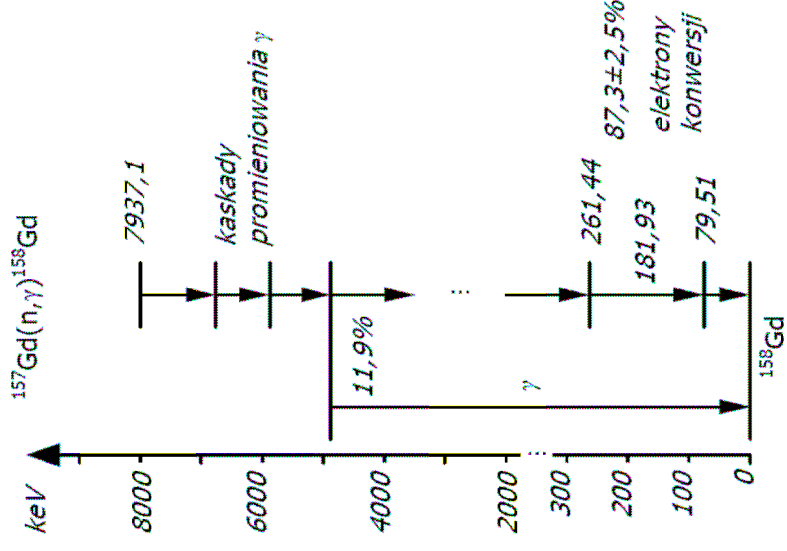
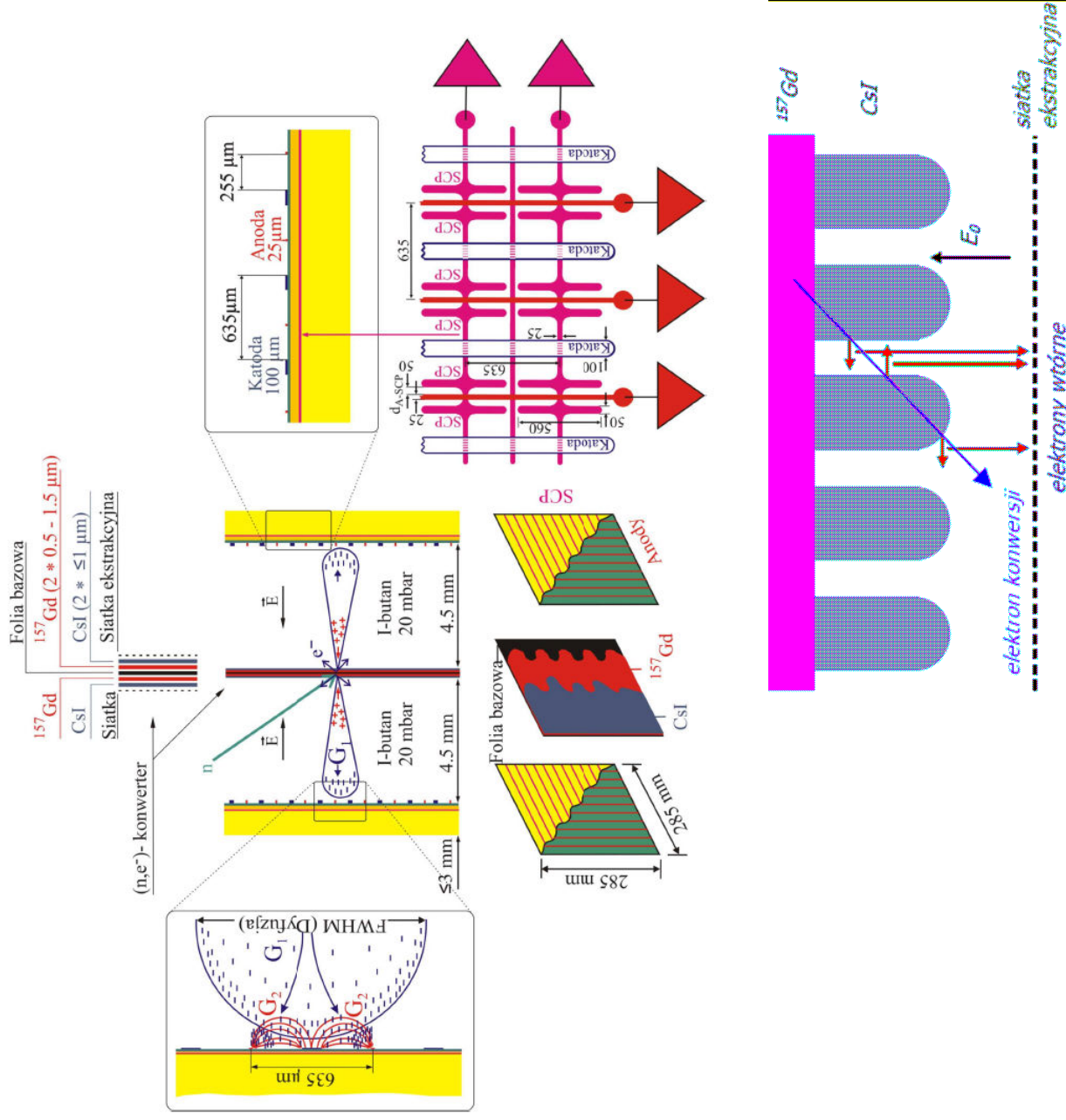
NMI3 – Integrated Infrastructure Initiative for Neutron Scattering and Muon Spectroscopy

- **Przeznaczenie układu scalonego i założenia projektowe**
- **Układ pomiarowy**
- **Parametryzacja analogowa**
 - przetworniki cyfrowo-analogowe (dyskryminacja)
 - korekta offsetu (trimming)
 - kanał energetyczny (slow shaper)
 - kanał czasowy (fast shaper)
- **Parametryzacja czasowa**
- **Pomiary ze źródłem promieniowania**

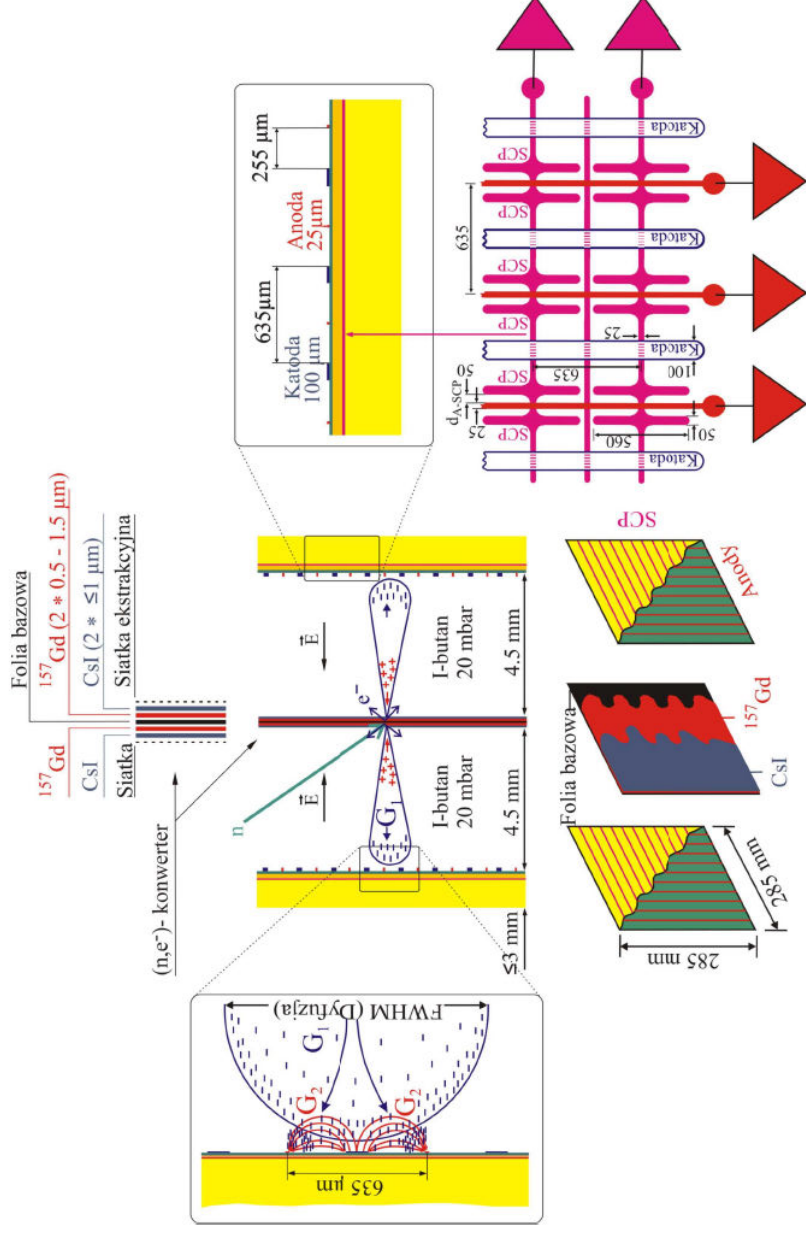
$^{157}\text{Gd}/\text{CsI}$ MSGC - detektor neutronów



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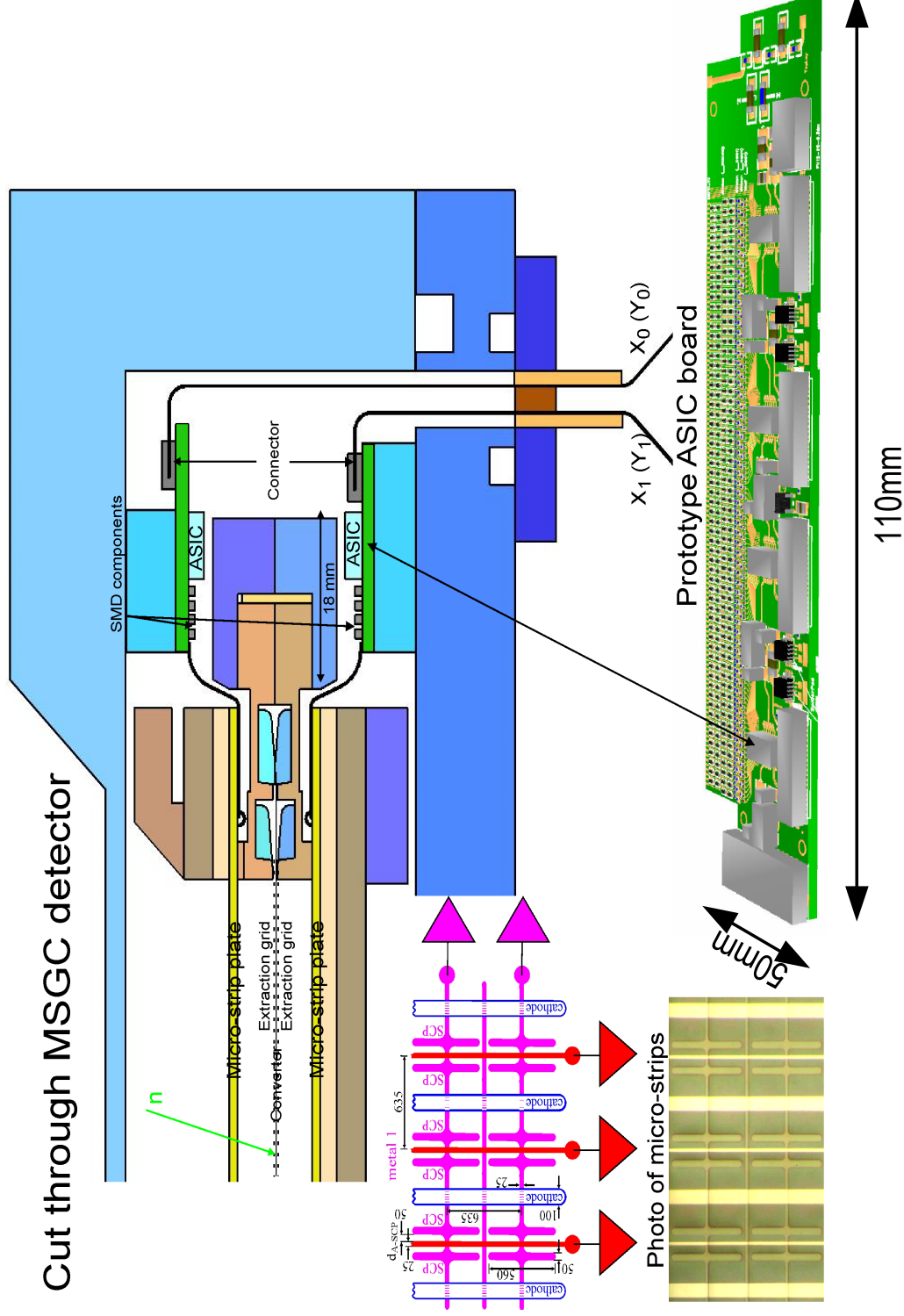


$^{157}\text{Gd}/\text{CsI}$ MSGC - detektor neutronów

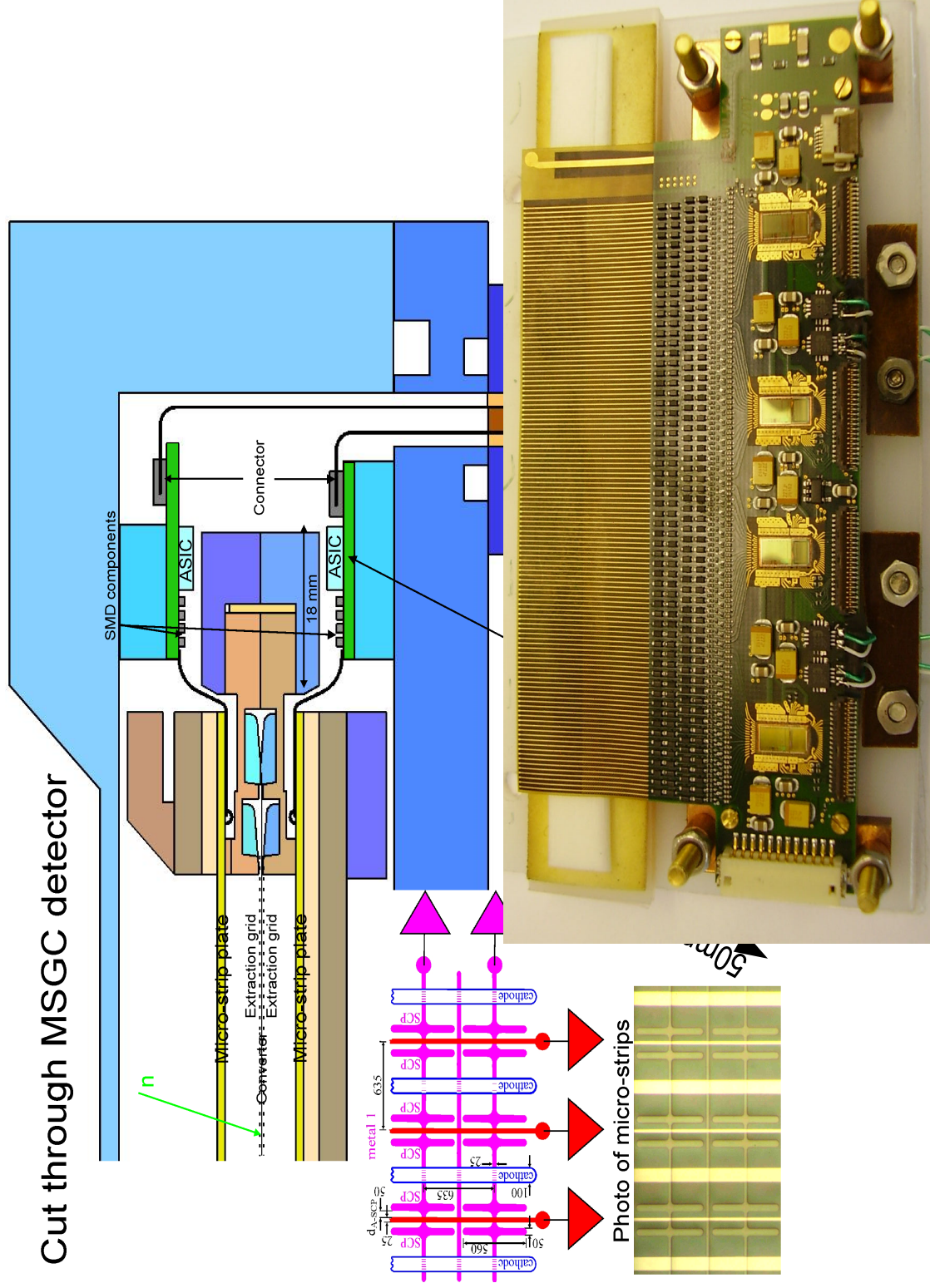


Segment size	285x285 mm² (active: 254x254 mm²)
Module size	570x570 mm² (2x2 segments)
Micro-strip pitch	635μm
No. of micro-strip per segment	400x400 (121x121) !!!
No. of ASICs (32 ch.) per segment	13x13 (4x4) !!!

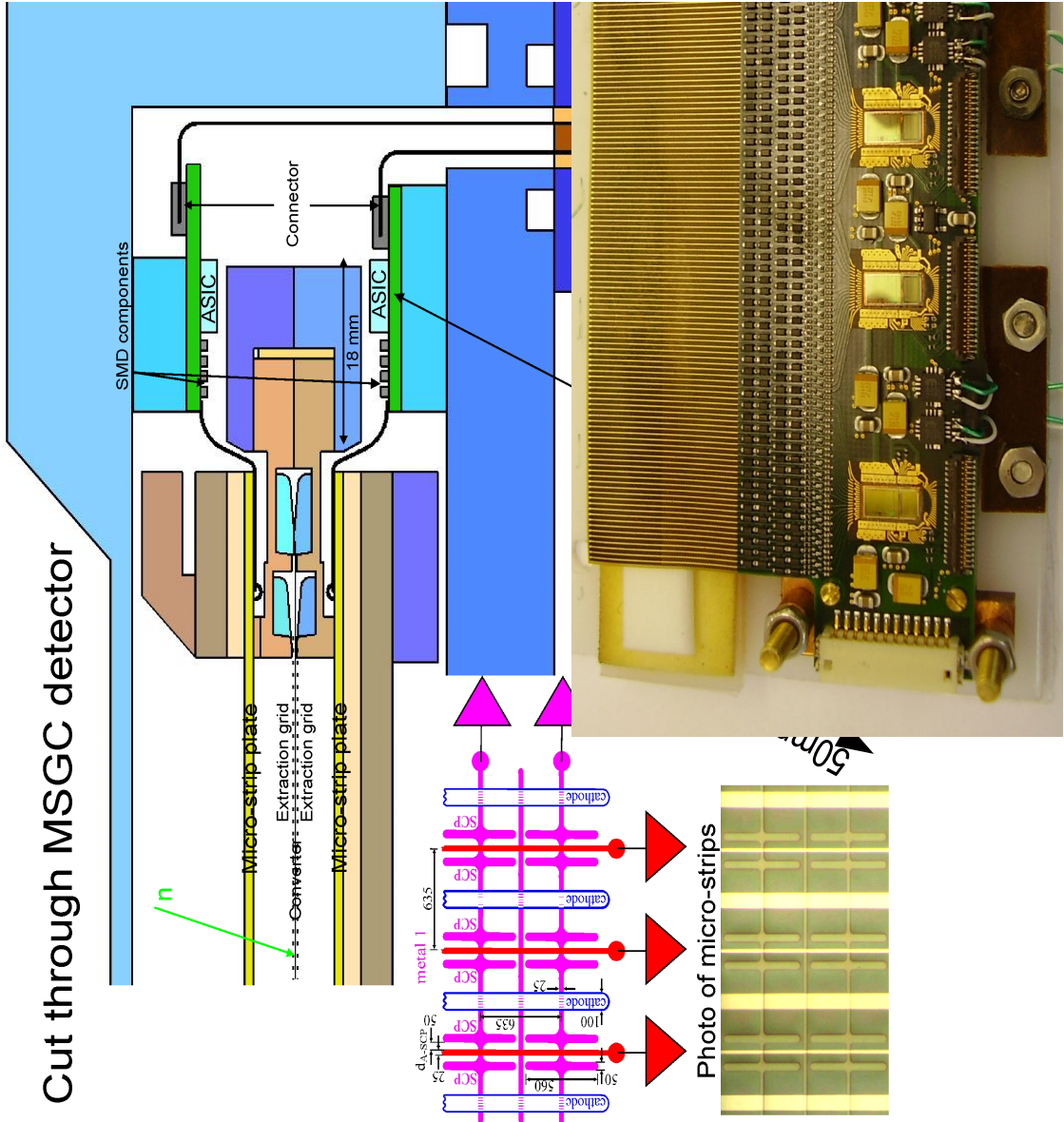
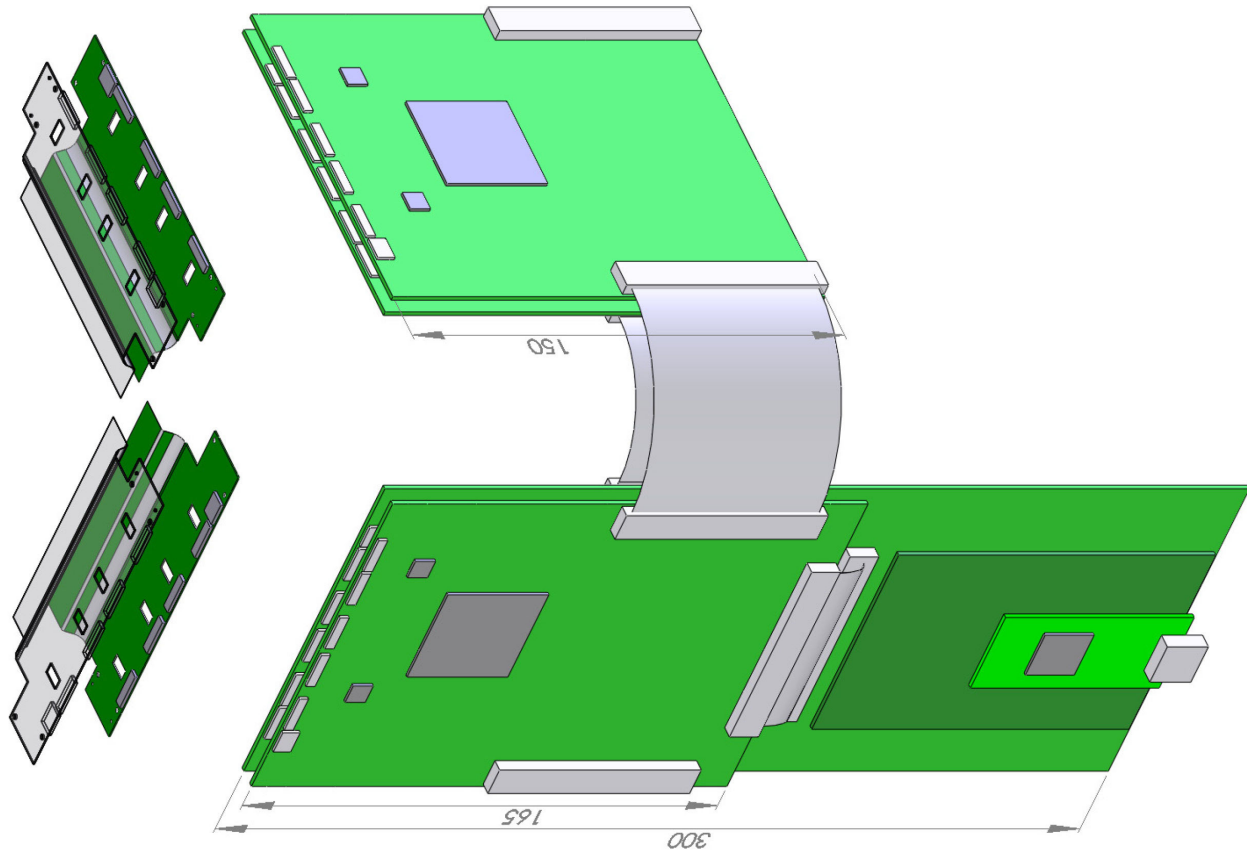
$^{157}\text{Gd}/\text{CsI MSGC}$ – system odczytowy



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157Gd/CSI MSGC – system odczytowy



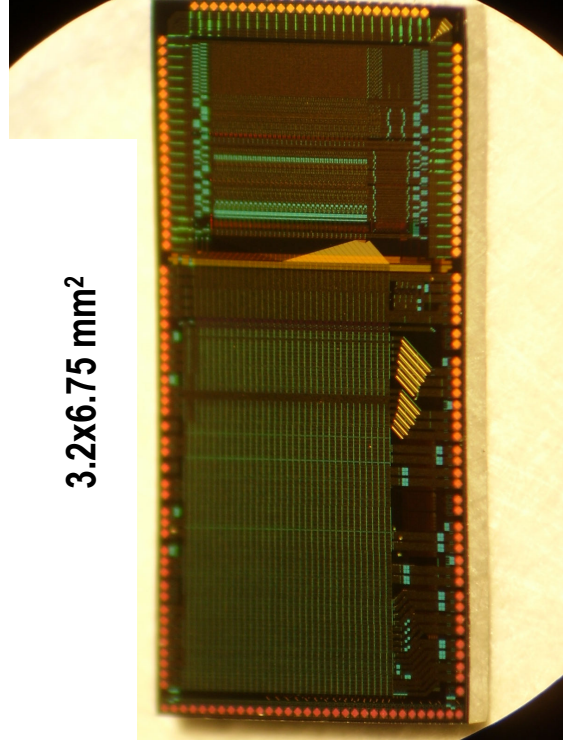
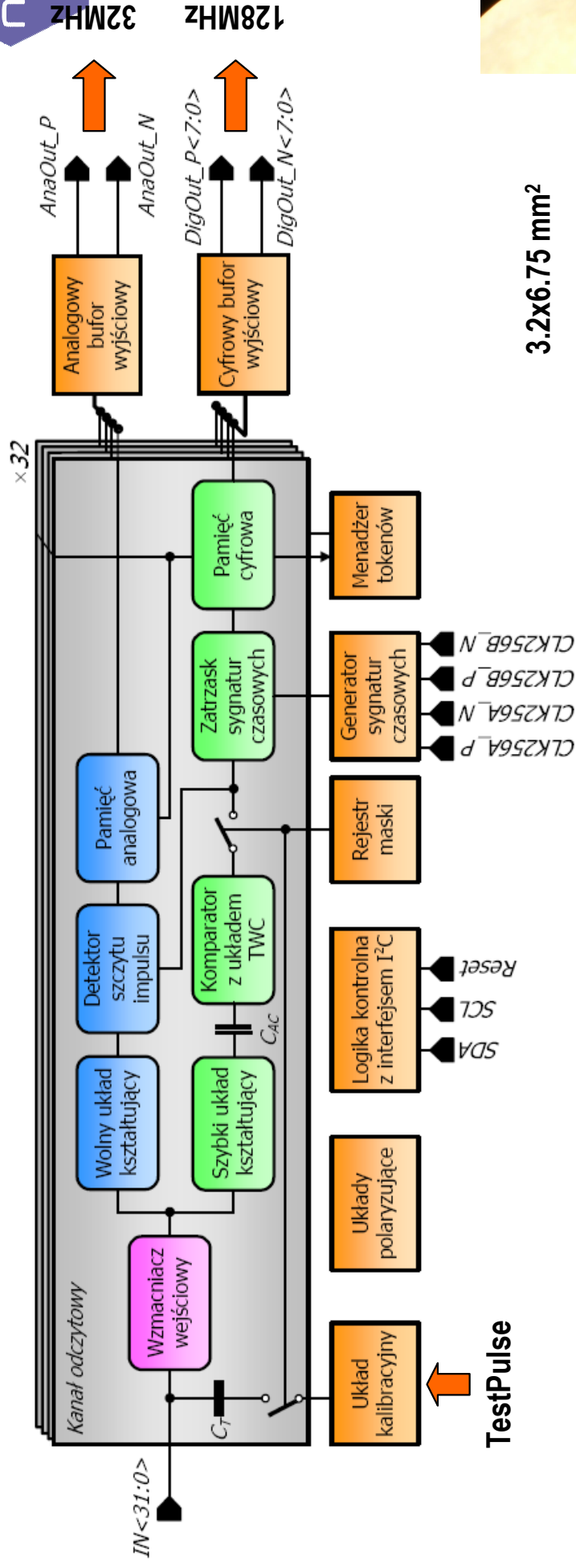
Cut through MSGC detector

MSGROC – założenia projektowe



Parametry ekstrahowane z sygnału wejściowego	X/Y, T, E _x /E _y
Liczba kanałów na jeden układ	32
Średnia częstość zliczeń na jeden kanał [1/s]	9 · 10 ⁵
Średnia częstość zliczeń na segment [1/s]	~ 10 ⁸
Ładunek na wejściu [e-]	2 · 10 ⁵ (32fC) ÷ 5 · 10 ⁶ (800fC)
Prog dyskryminacji	5σ = 10 ⁴ e- (3.2fC)
Przedział czasowy dla koincydencji zdarzeń X/Y [ns]	2
Czas kształtowania w torze czasowym [ns]	25
Czas martwy [ns]	~ 120
ENC (σ rms) [e-] @ C _{det} = 30pF	~ 2000 (0.32fC)

MSGCROC – architektura układu scalonego



3.2x6.75 mm²

- obie polarności (pos. & neg.)
- $T_{\text{peak}} = 25\text{ns}$ (fast shaper), $T_{\text{peak}} = 85\text{ns}$ (slow shaper)
- pamięć analogowa (4 – FIFO)
- pamięć cyfrowa (4 – FIFO)
- dyskryminator: time walk < 2 ns, jitter < 1 ns FWHM
- 5-bit trimming DAC

Układ pomiarowy



SUCIMA - VIRTEX II XC2V1000 4FG456CES (324 I/O)

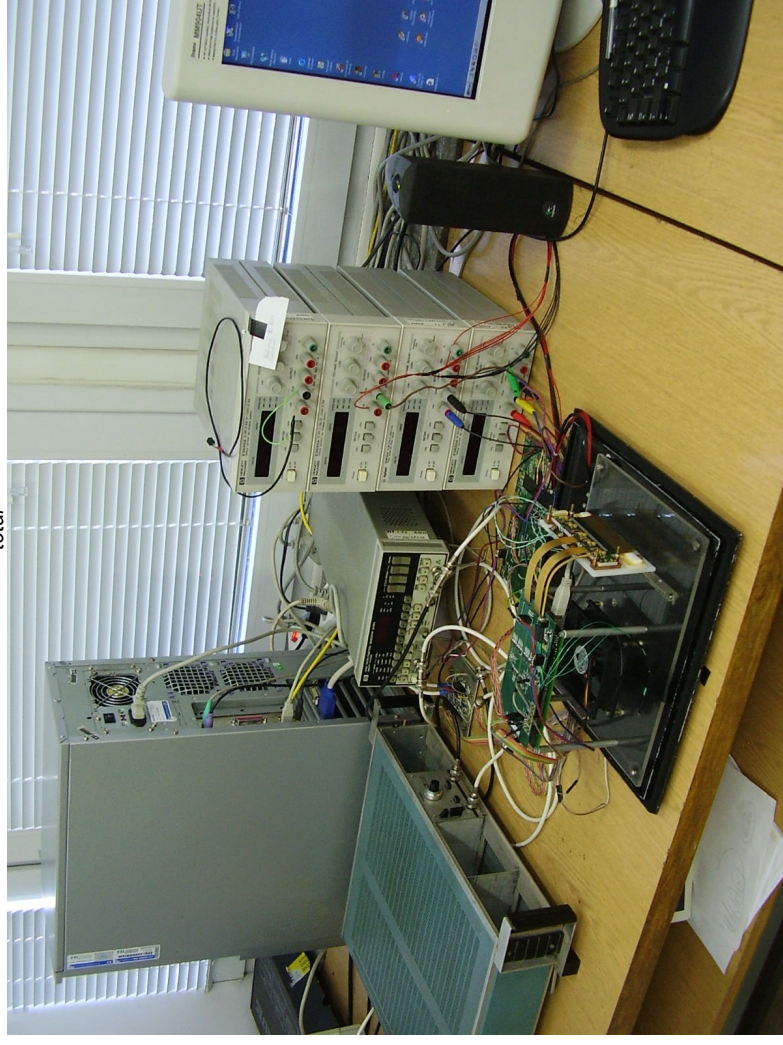
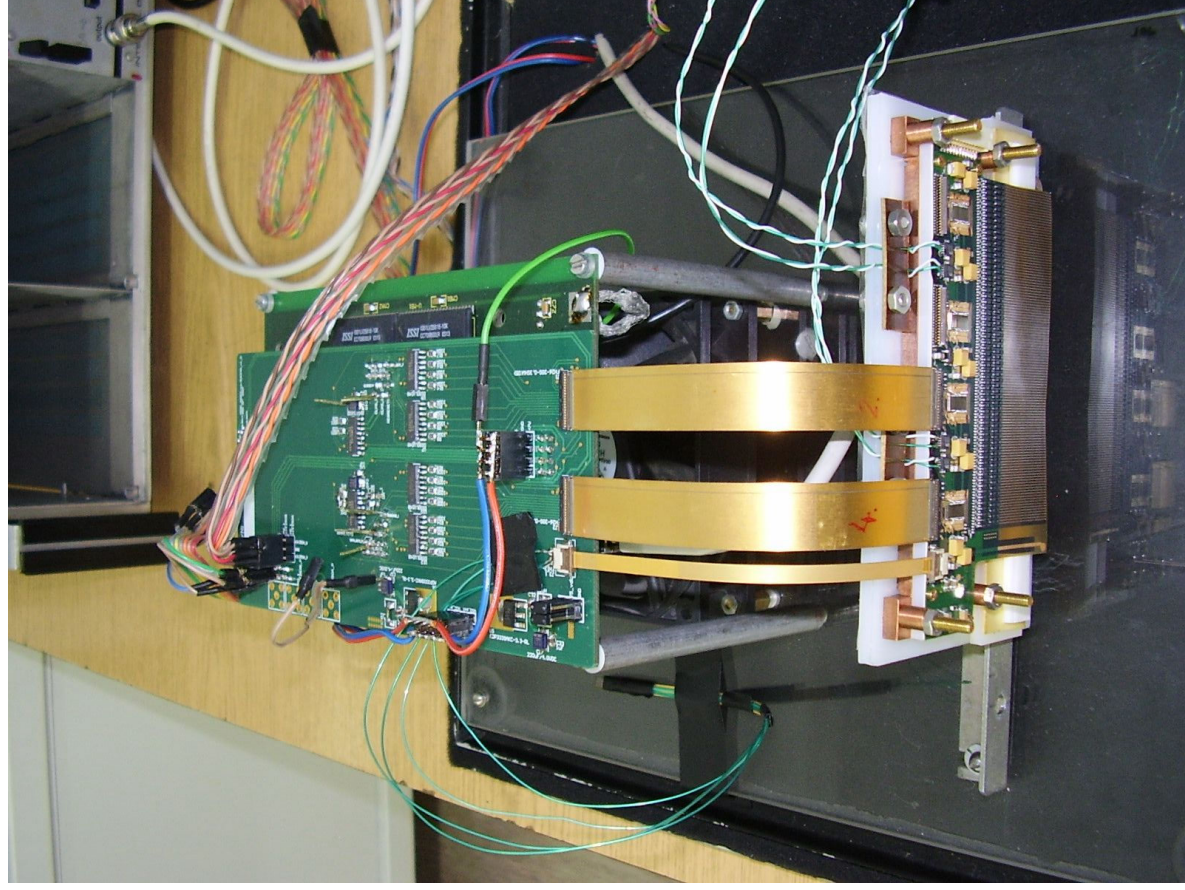
+ ADC 12-bit, 65MSPS (AD9226)

VDDA= 3.3VDC, $I_{VDDA} = 250\text{mA} / \text{ASIC}$

VDDA_buf= 3.3VDC, $I_{VDDA_buf} = 2.4\text{mA} / \text{ASIC}$

VDD= 3.3VDC, $I_{VDD} = 42\text{mA} / \text{ASIC} @ f_{\text{clk}256\text{AB}} = 256\text{MHz}$

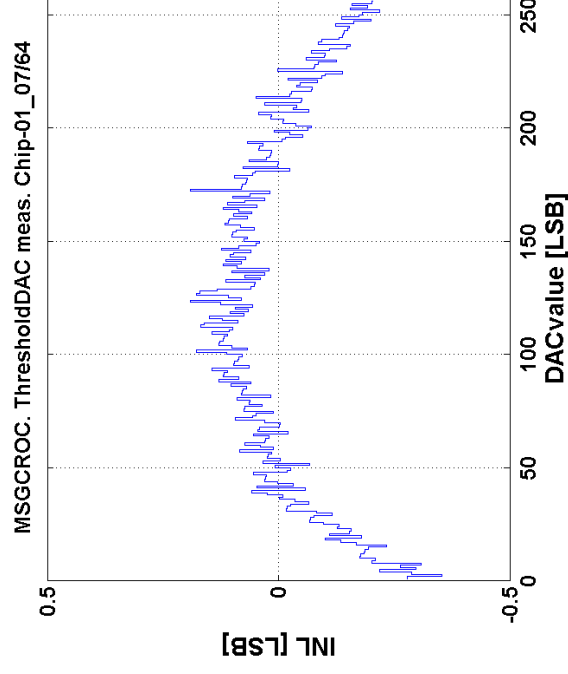
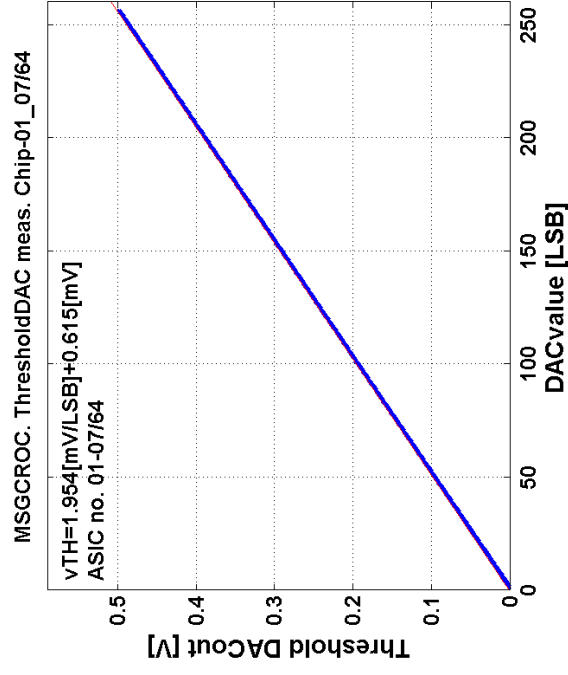
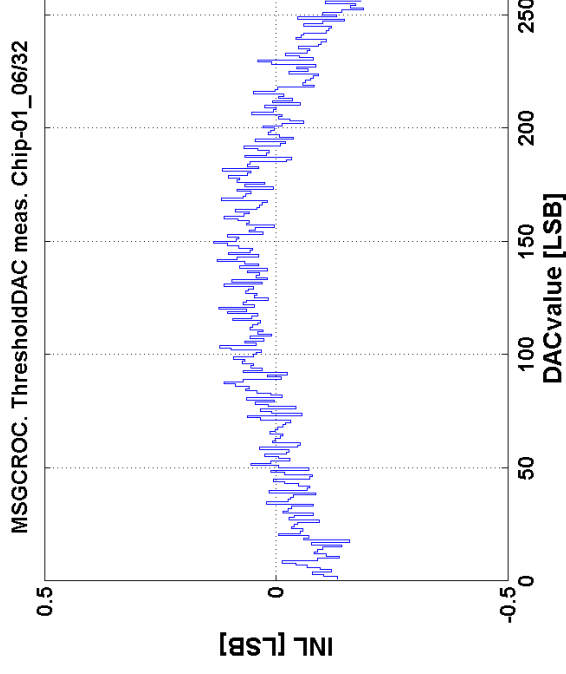
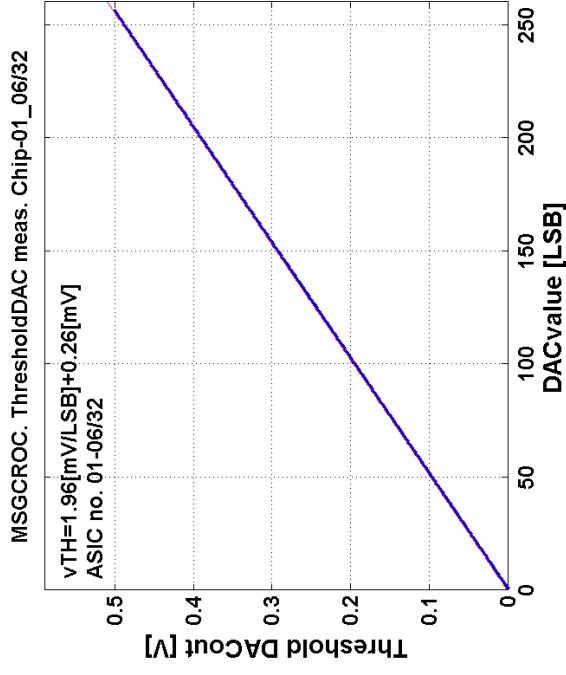
$P_{\text{total}} \approx 1\text{W} / \text{ASIC}$



Przetworniki cyfrowo - analogowe (DACs)

DAC Name	Type	Nominal	RealRange	Default value	DAC's LSB	Notes
iPRE	IDAC(8b)	(124LSB) 250 mA	(0; 506.9) mA	255 mA	1.9714 mA	Preamplifier current (bias)
iSH	IDAC(8b)	(122LSB) 100 mA	(0; 206.5) mA	103 mA	0.8061 mA	Shapers current (bias)
iPDH	IDAC(8b)	(98LSB) 80 mA	(0; 206.5) mA	103 mA	0.8061 mA	PDH current (bias)
vPDH	VDAC(8b)	(101LSB) 740 mV (extr.)	(0; 1.868) V	933 mV	7.3201 mV	PDH reset voltage
iCOMP	IDAC(8b)	(121LSB) 50 mA	(0; 103.7) mA	53.2 mA	0.4035 mA	Comparator current (bias)
iTWC	IDAC(8b)	(114LSB) 60 mA	(0; 133.0) mA	66.7 mA	0.5175 mA	TWC current (bias)
iINV	IDAC(8b)	(77LSB) 83 mA (extr.)	(0; 269.6) mA	134.6 mA	1.052 mA	TWC output stage current (2 nd TH stage)
iOUTBUF	IDAC(8b)	(117LSB) 148 mA	(0; 324.7) mA	165 mA	1.269 mA	Analog output buffer current (bias)
iDUR	IDAC(8b)	(78LSB) 50 mA	(0; 162.8) mA	81.2 mA	0.6363 mA	Monostable pulse duration time
vTH	VDAC(8b)	(14LSB) 30 mV	(0; 519.9) mV	267 mV	2.0348 mV	Threshold
cal	VDAC(8b)	(23LSB) 50fC(min)	(0; 470) fC	0 fC	1.8127 mV	$C_{\text{rest}}=1\text{pF}$, calibration voltage step high
itrim	IDAC(5b)	(16LSB) 100 mA	(0; 188.5) mA	0 mA	6.0802 mA	Total range of IDAC divided by 49 in current mirror

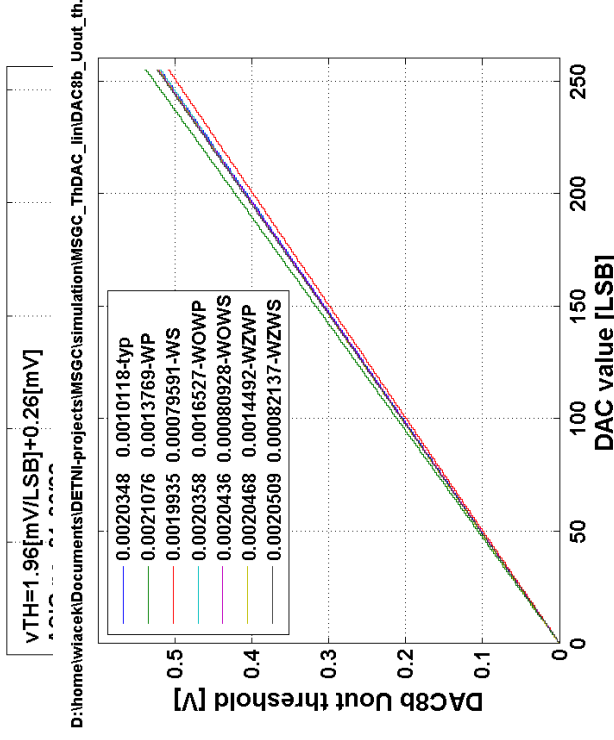
DAC - dyskryminacja



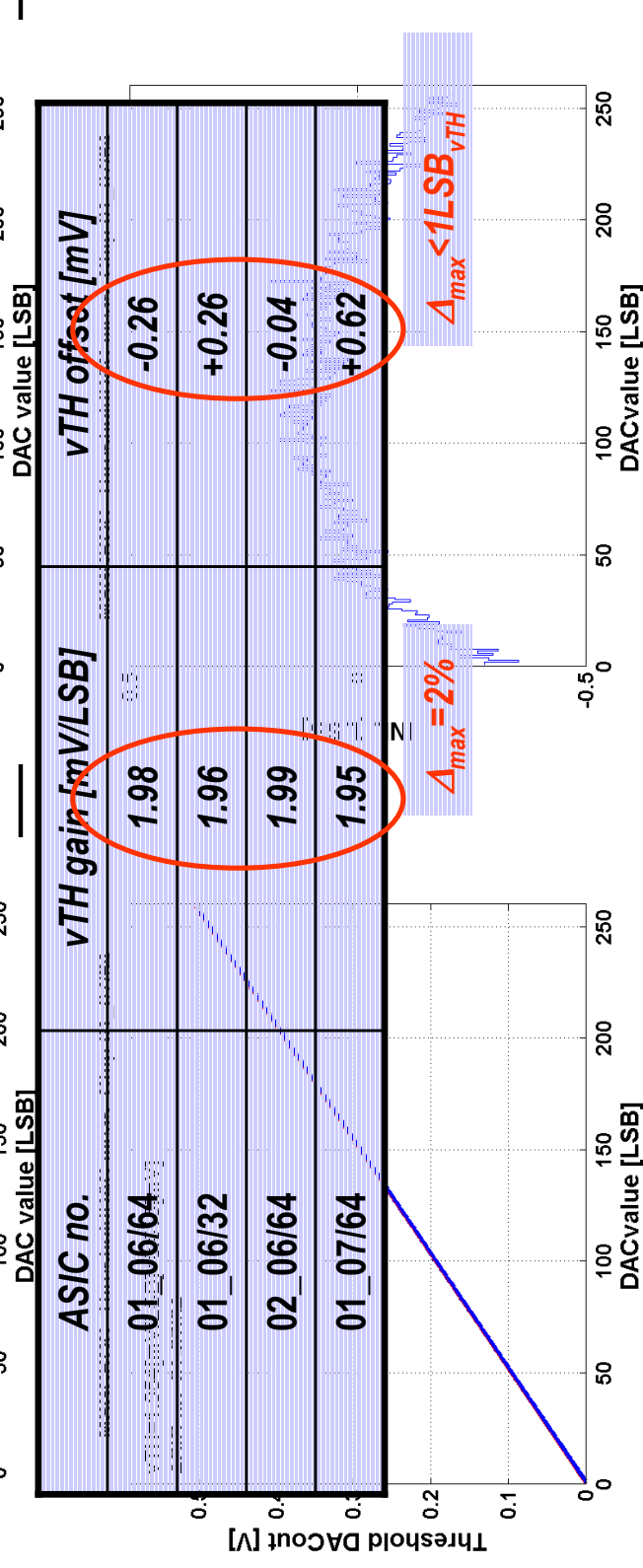
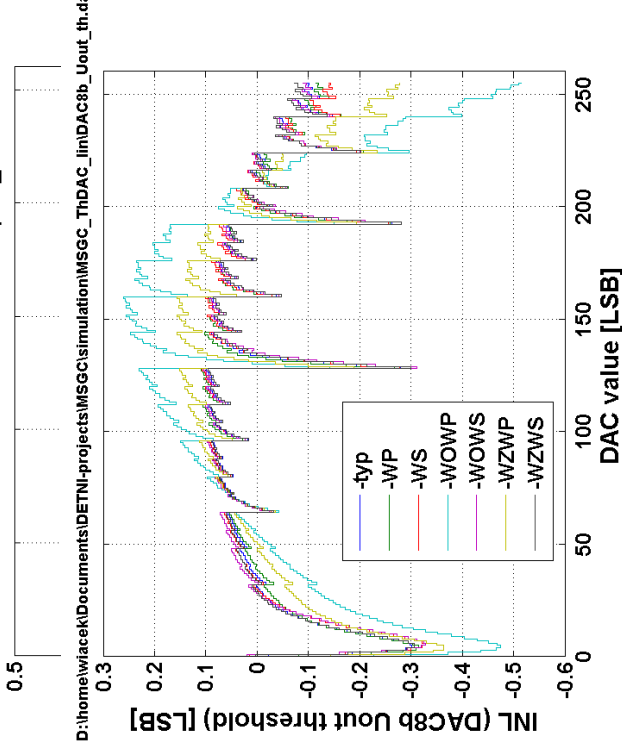
DAC - dyskryminacja



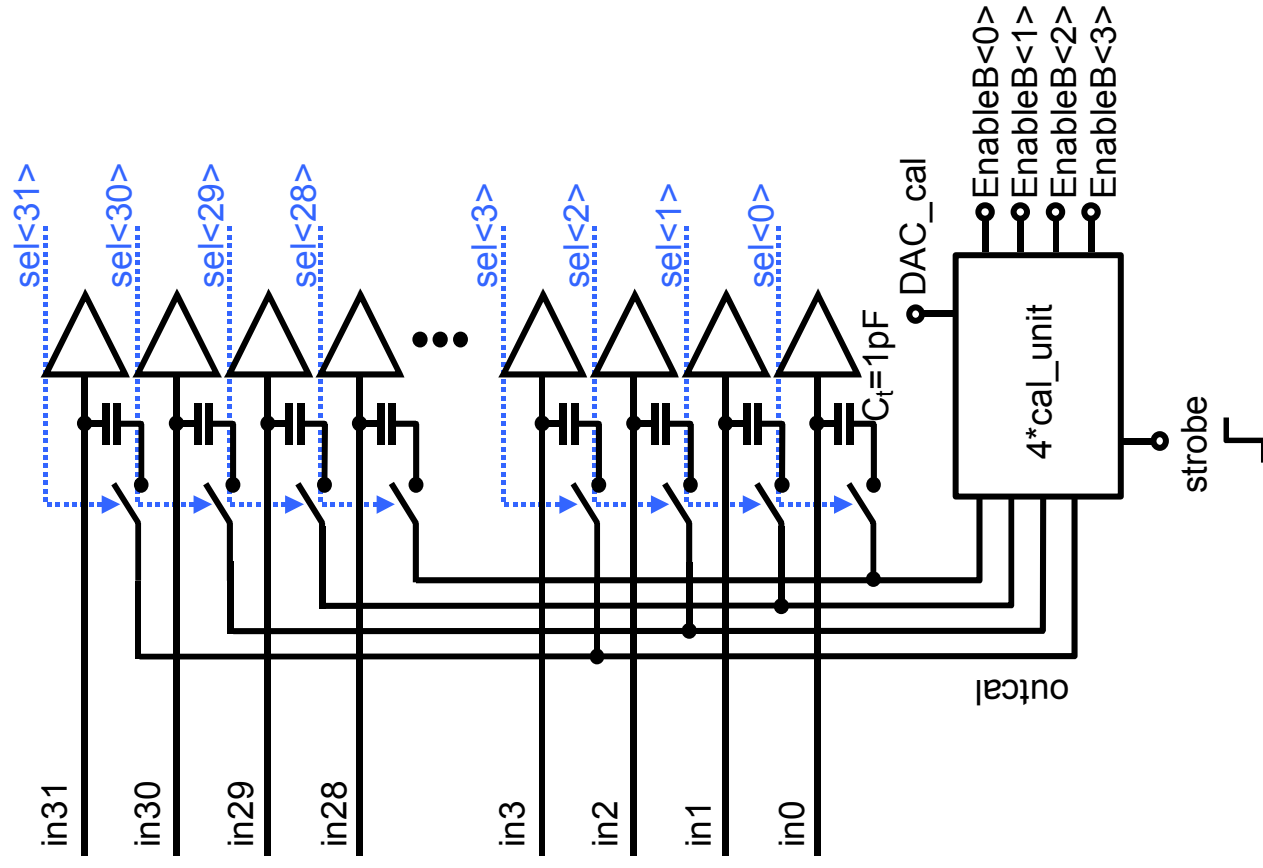
MSGCROC. ThresholdDAC meas. Chip-01_06/32



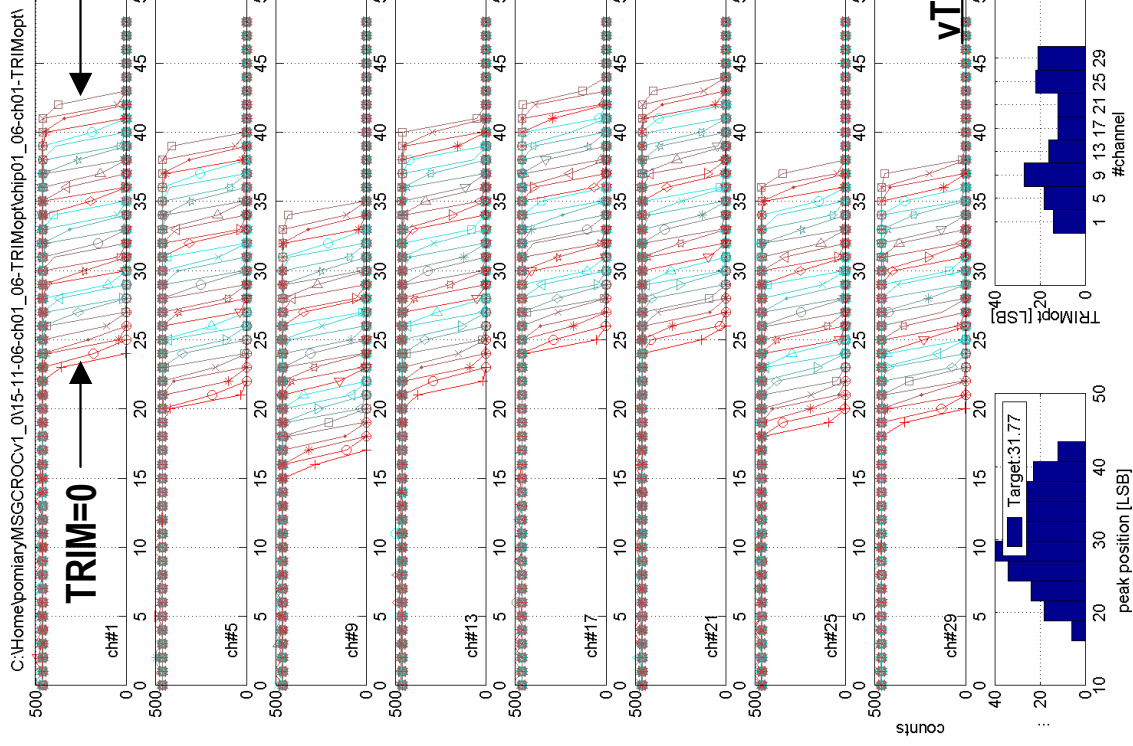
MSGCROC. ThresholdDAC meas. Chip-01_06/32



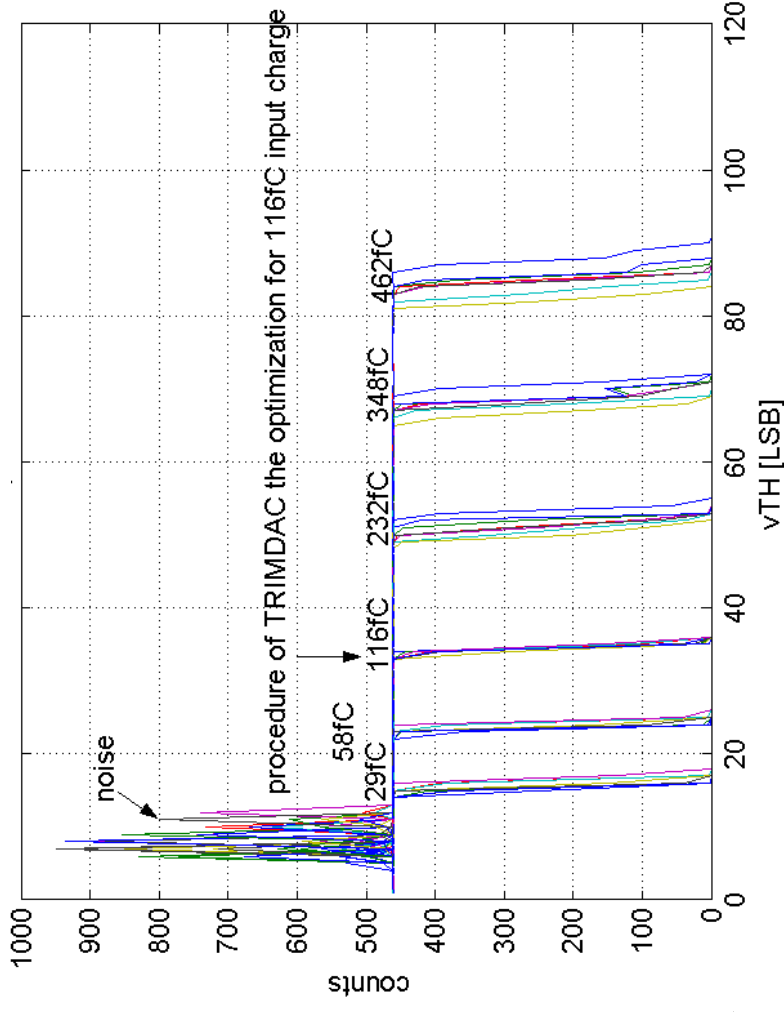
Układ kalibracyjny



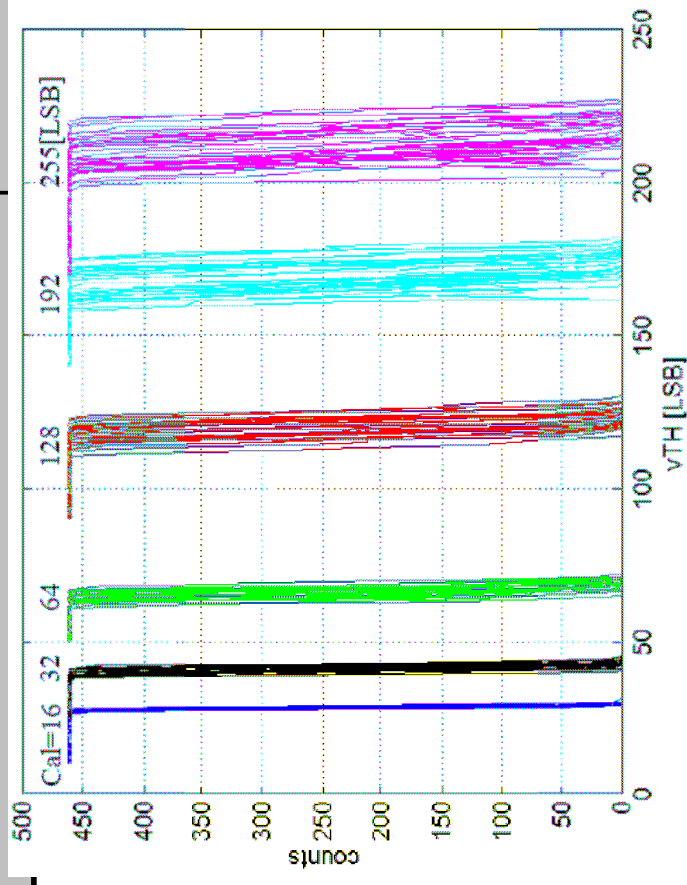
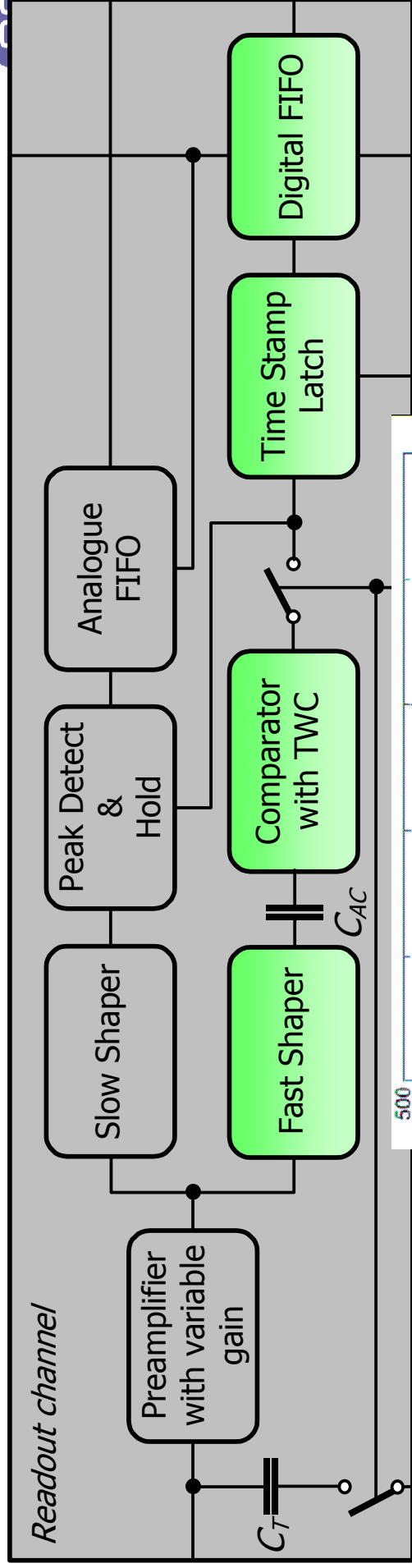
Korekta offsetu (trimming)



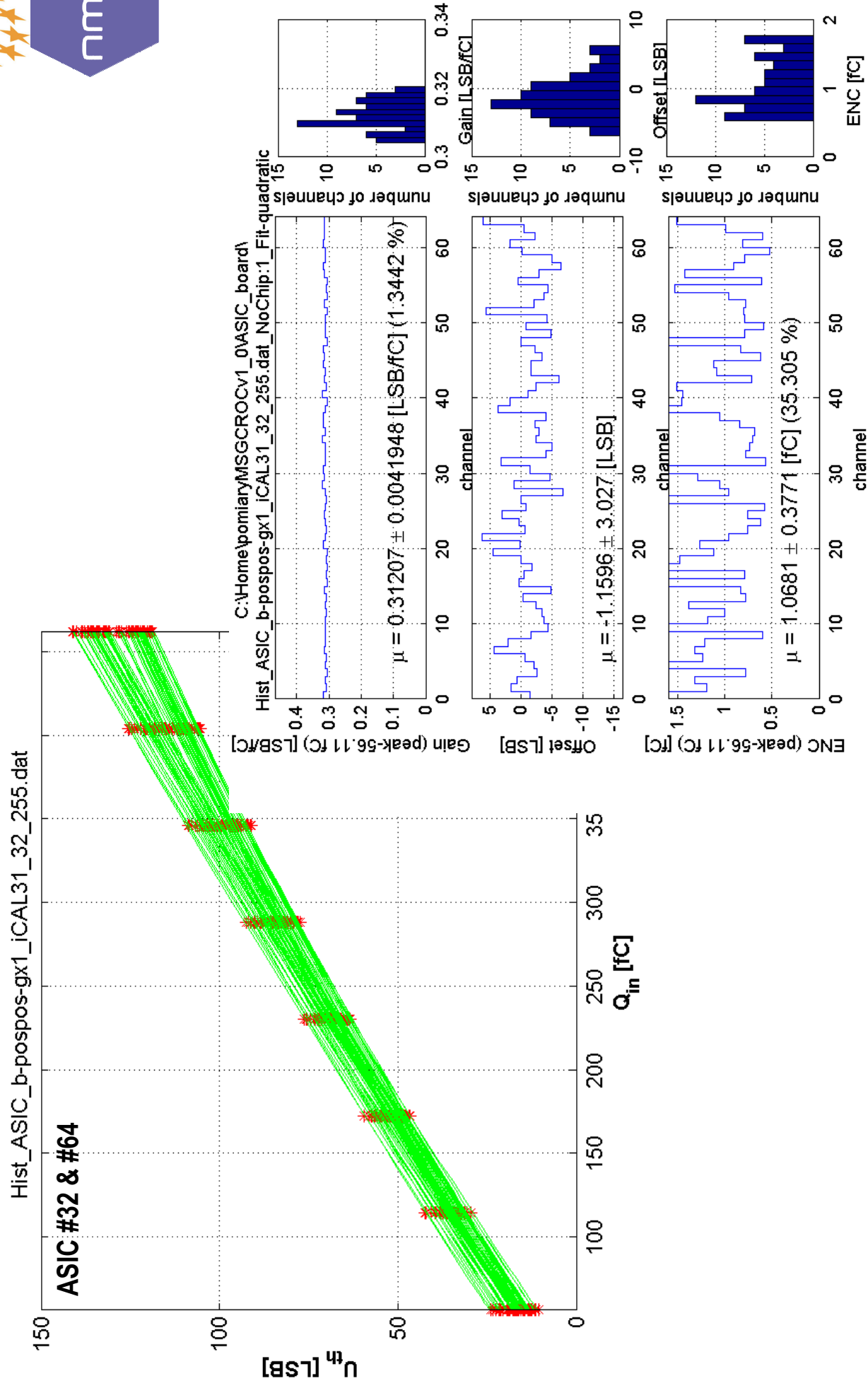
TRIM=31 [LSB] $v_{TRIM,LSB} \approx 1.2 \text{ mV}$ ($v_{TH,LSB} \approx 2 \text{ mV}$)



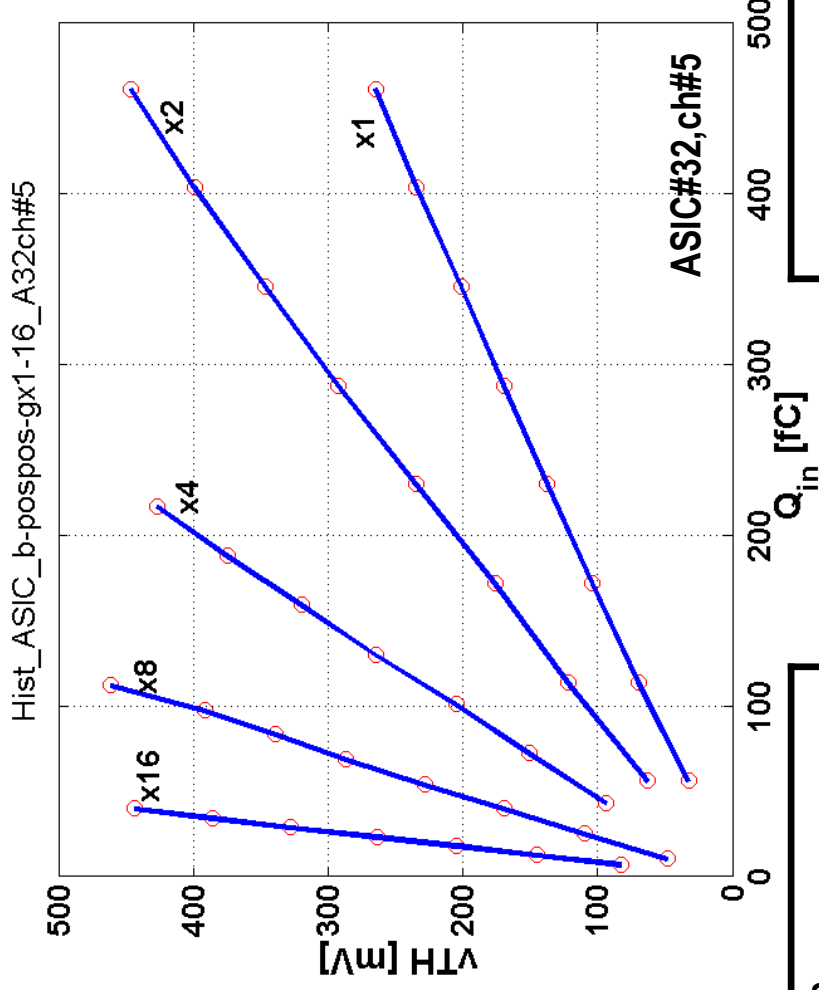
Kanał czasowy (fast shaper)



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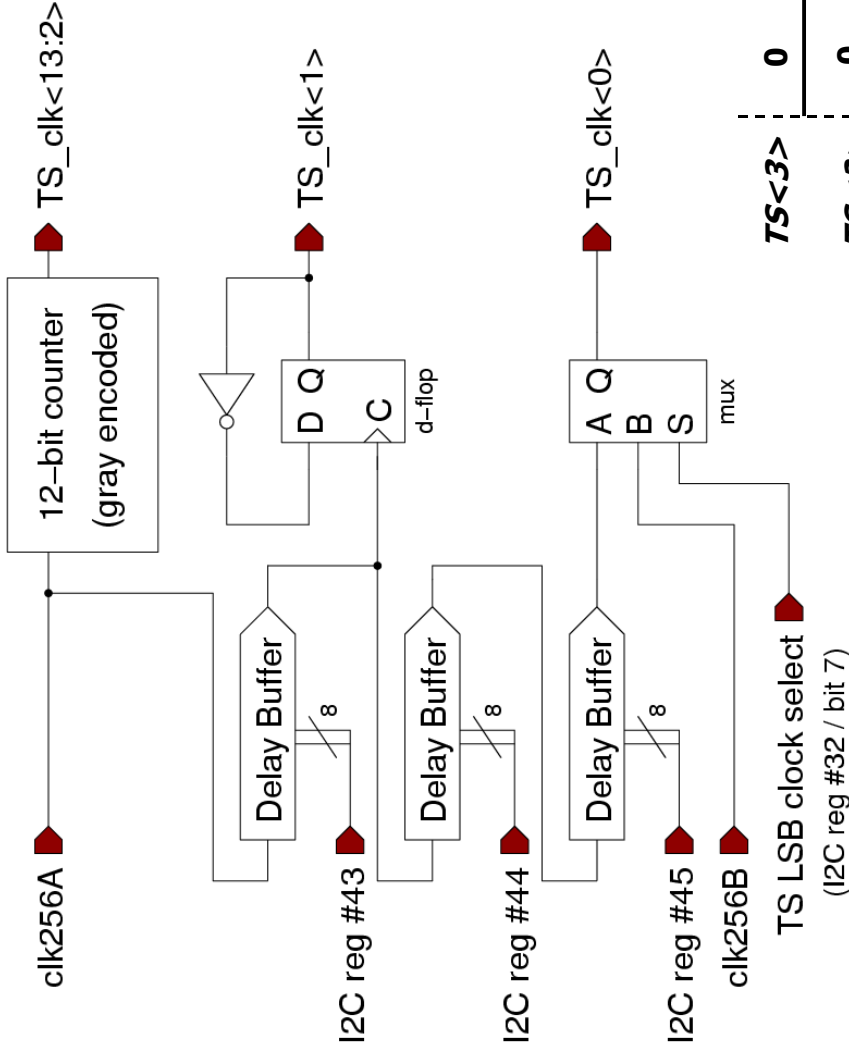
Kanał czasowy (fast shaper)



ASIC #32			
Gain [mV/fC]	Offset [mV]	ENC [fC]	
0.6223	-1.035	1.16	
1.0613	2.423	0.69	
2.0572	3.797	0.41	
4.1832	5.370	0.197	
11.609	0.025	0.082	

x1
x1.7
x3.3
x6.7
x18.7

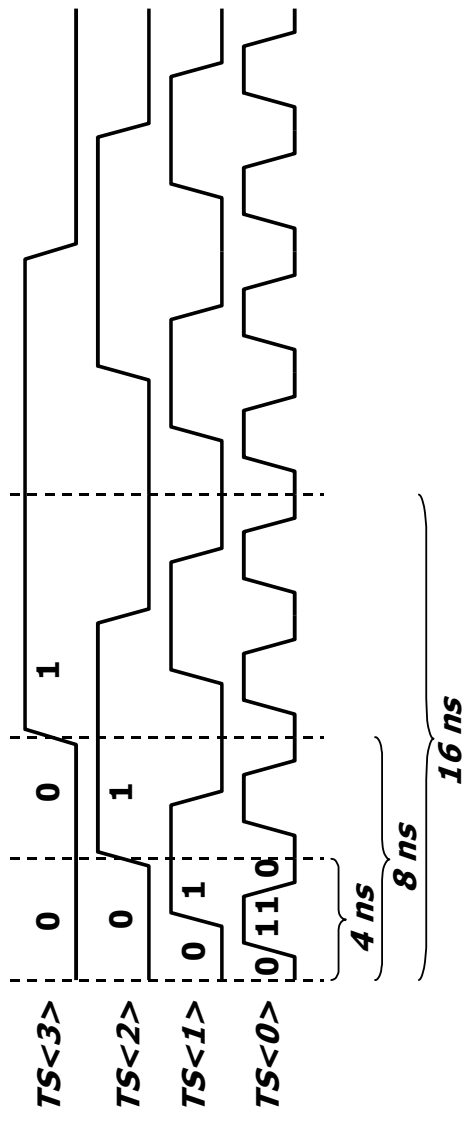
ASIC #64			
Gain [mV/fC]	Offset [mV]	ENC [fC]	
0.6259	-3.603	0.98	
1.0020	5.193	0.65	
1.8559	12.52	0.39	
3.9216	7.380	0.22	
11.084	2.268	0.091	



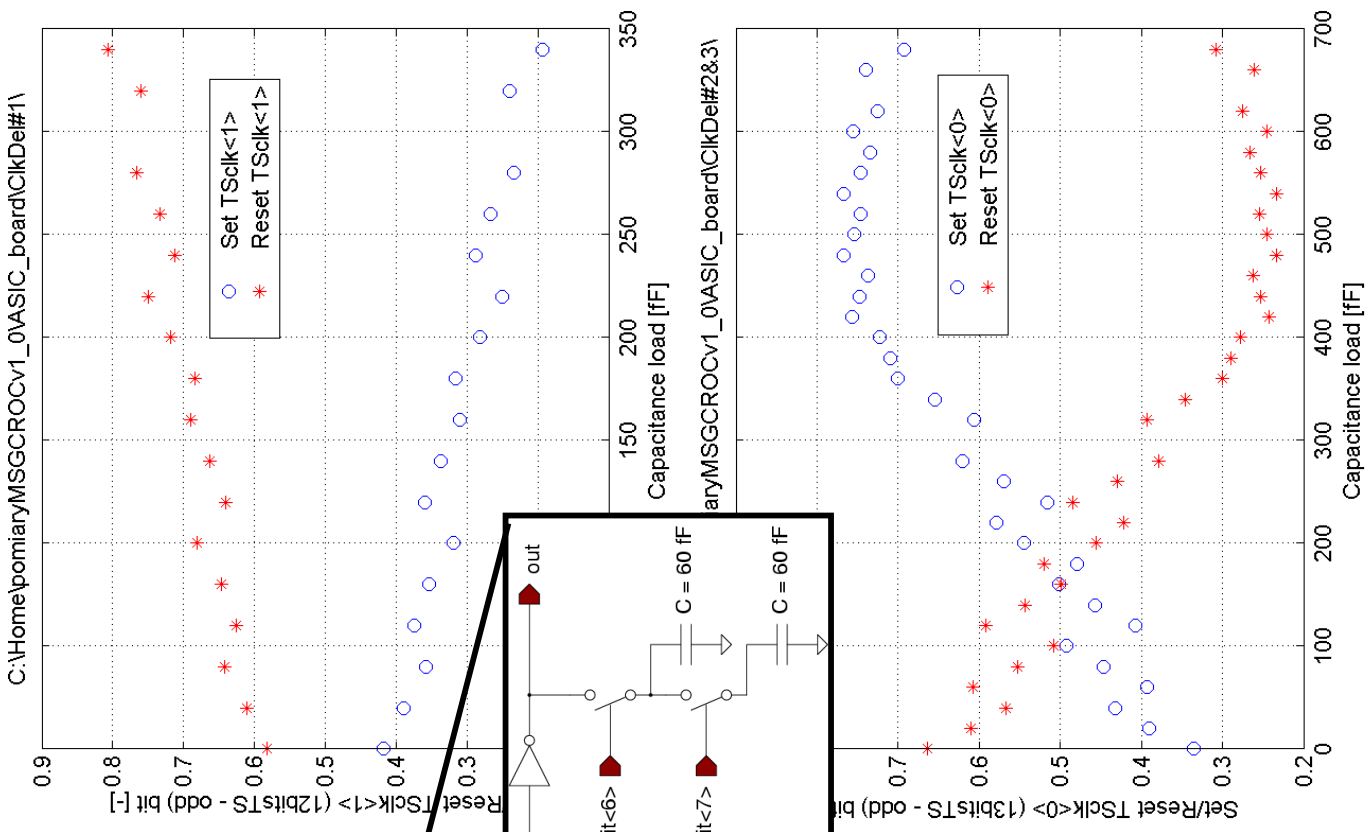
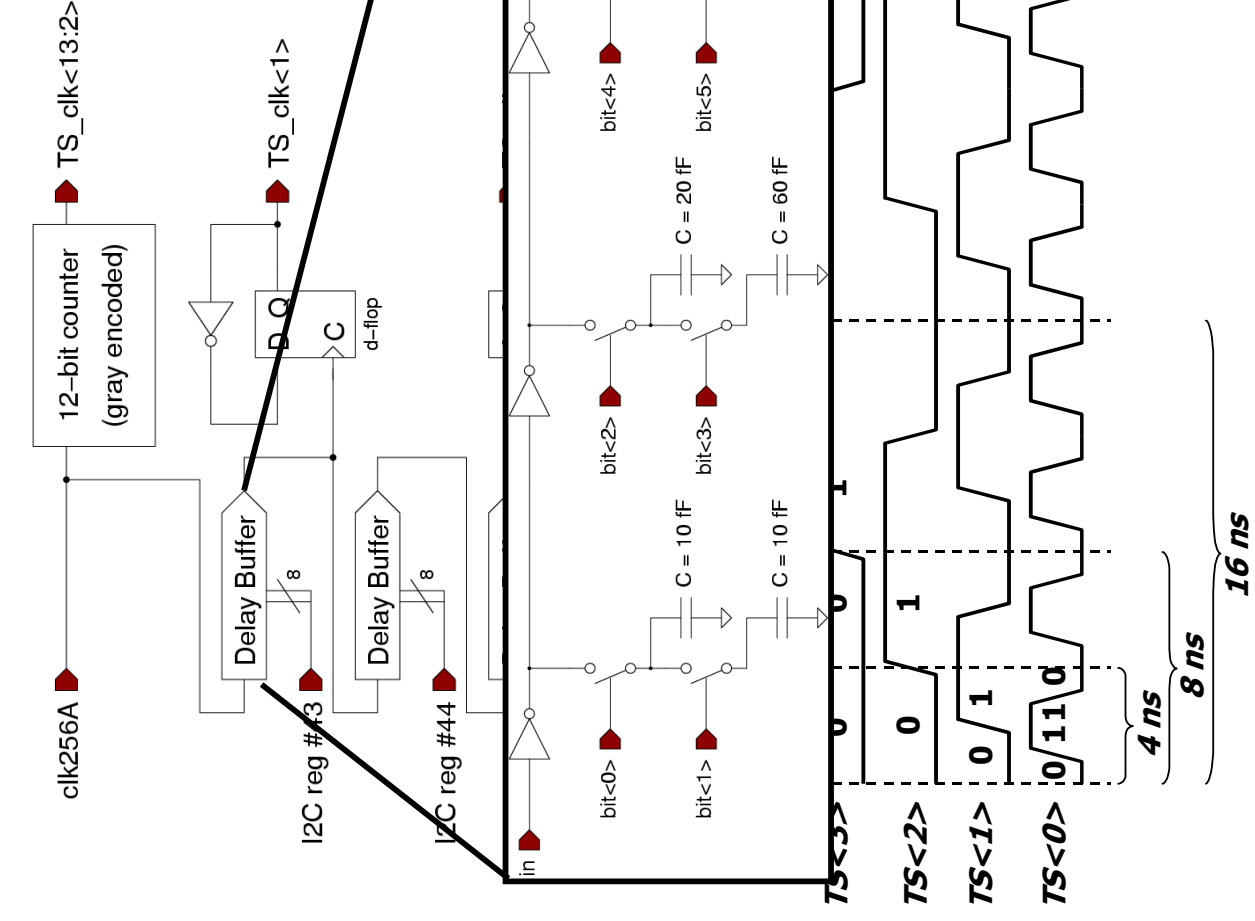
14-bit licznik sygnatur czasowych:

- 12-bit licznik kodu Gray'a,
- przerzutnik flip-flop,
- wejściowy zegar

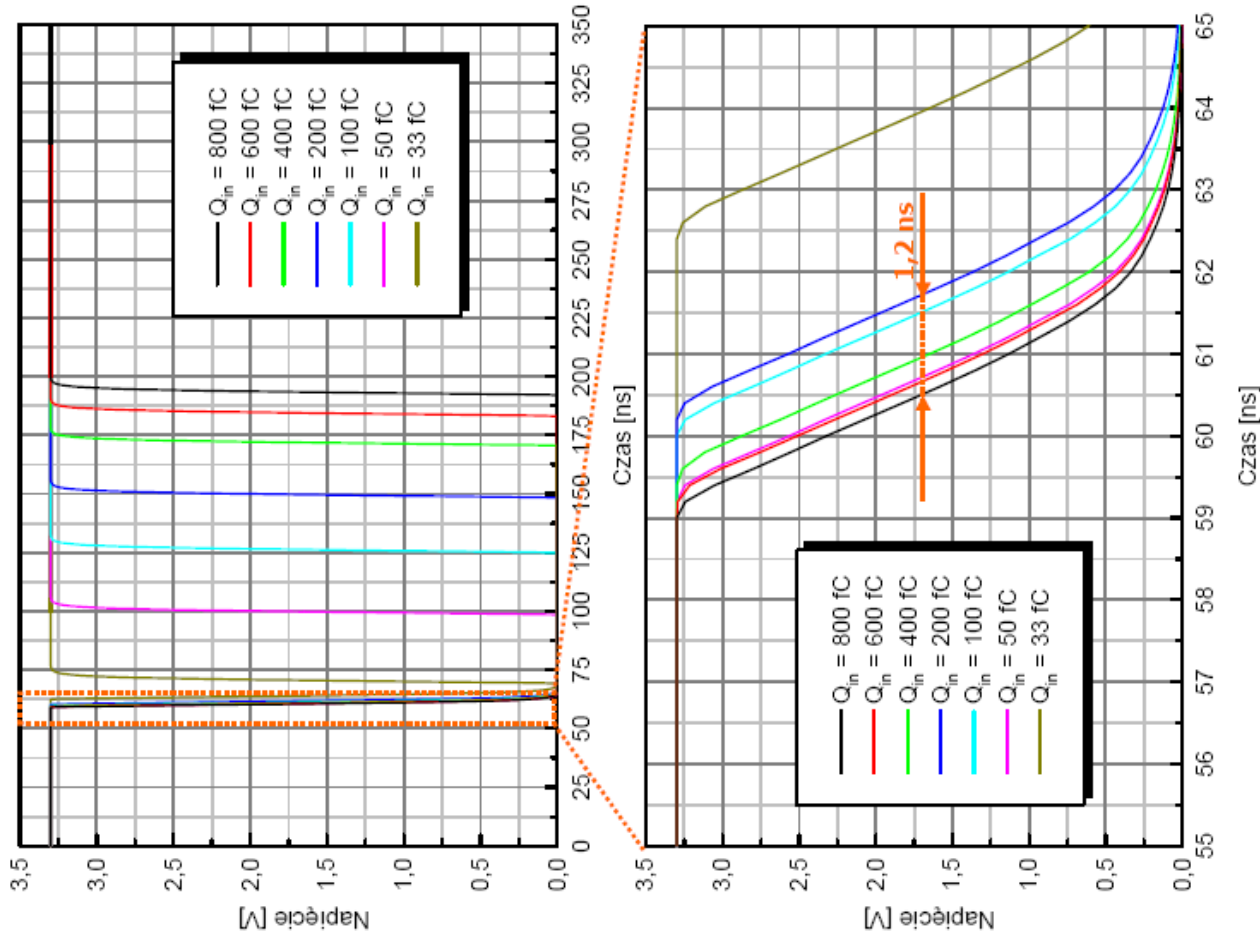
Dla wejściowego zegara 256MHz
rozdzielczość czasowa: **~1ns**



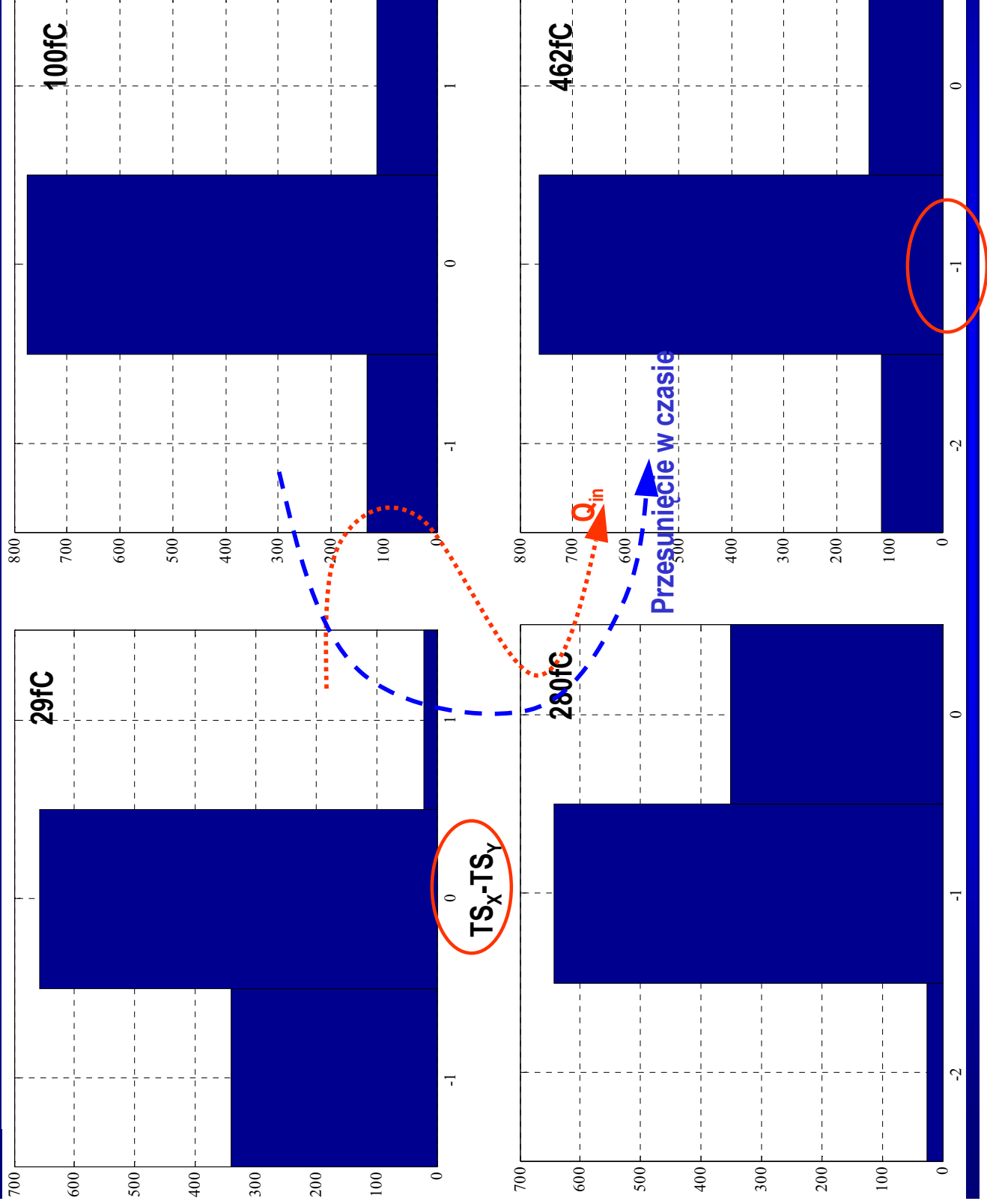
Parametryzacja czasowa



Kompensacja efektu wędrowania (time walk)

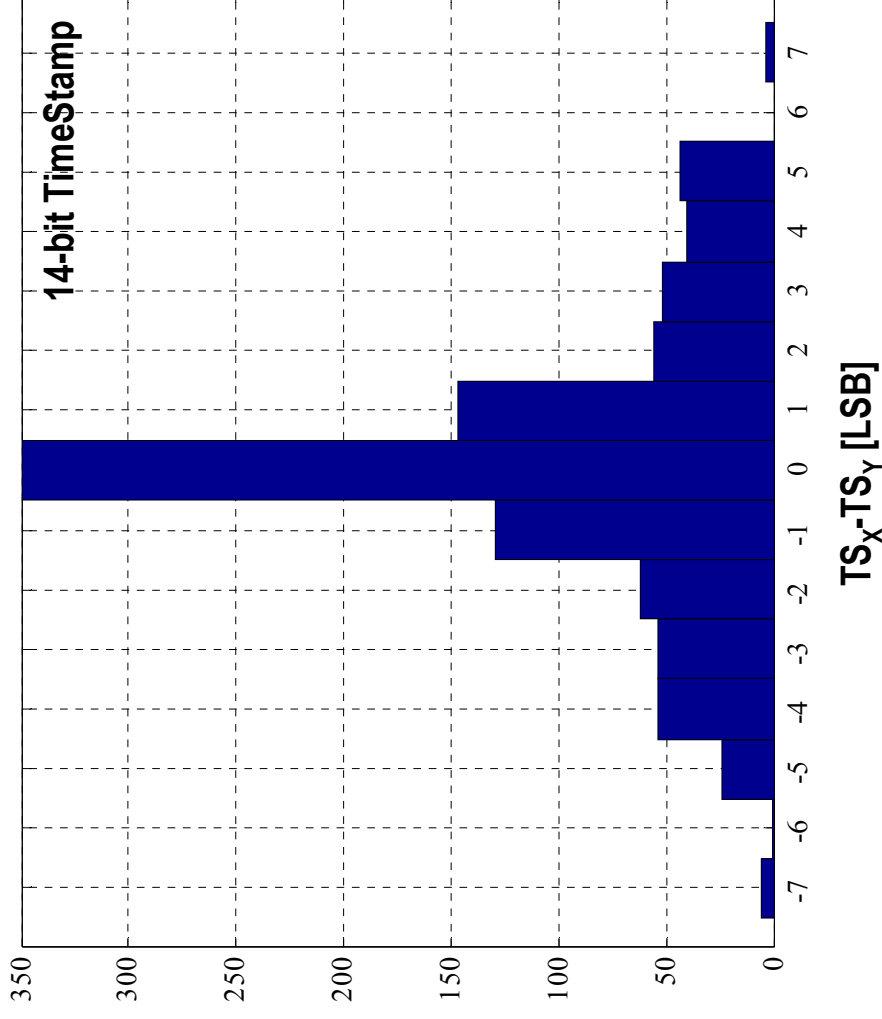


Kompensacja efektu wędrowania (time walk)



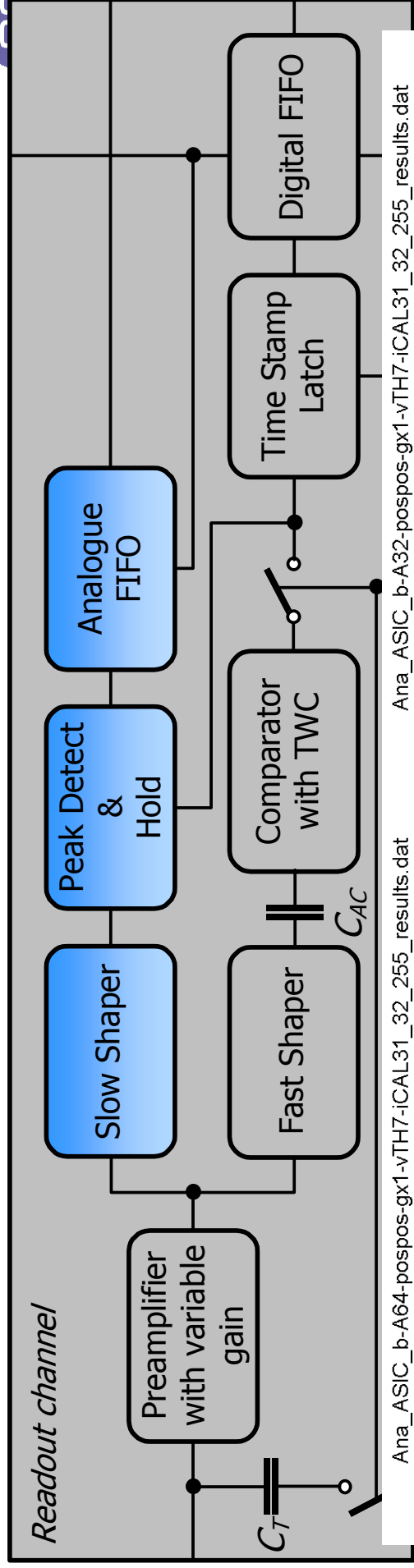
ical=10
(dyskryminacja)
Dla q_{in} od 33fC
do 462fC
Time Walk $\sim 4ns$
UWAGA:
histogramy dla
sygnatur 12-bit
TS

Efekt drżenia (jitter)

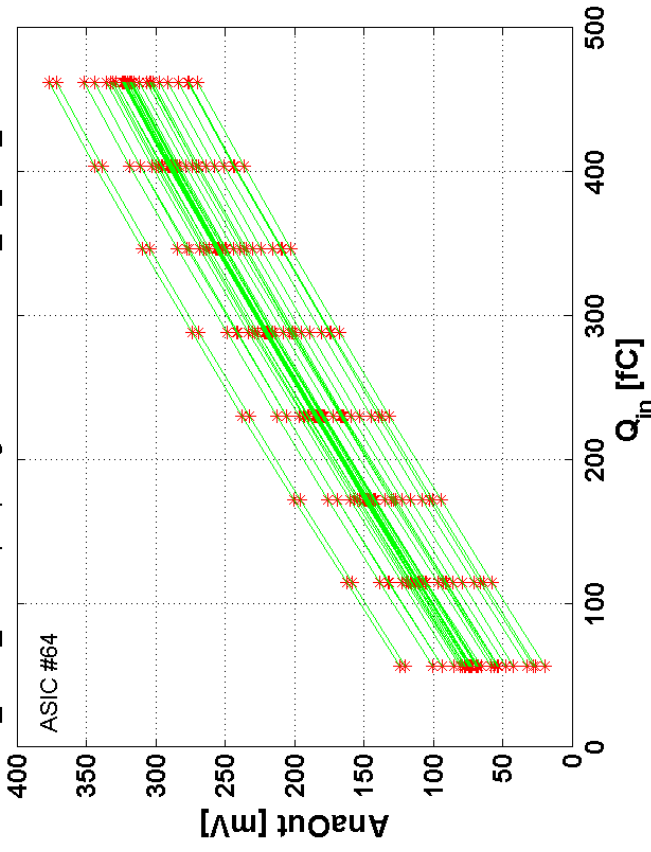


jitter ~1 [LSB_{14-bit}] (1ns)

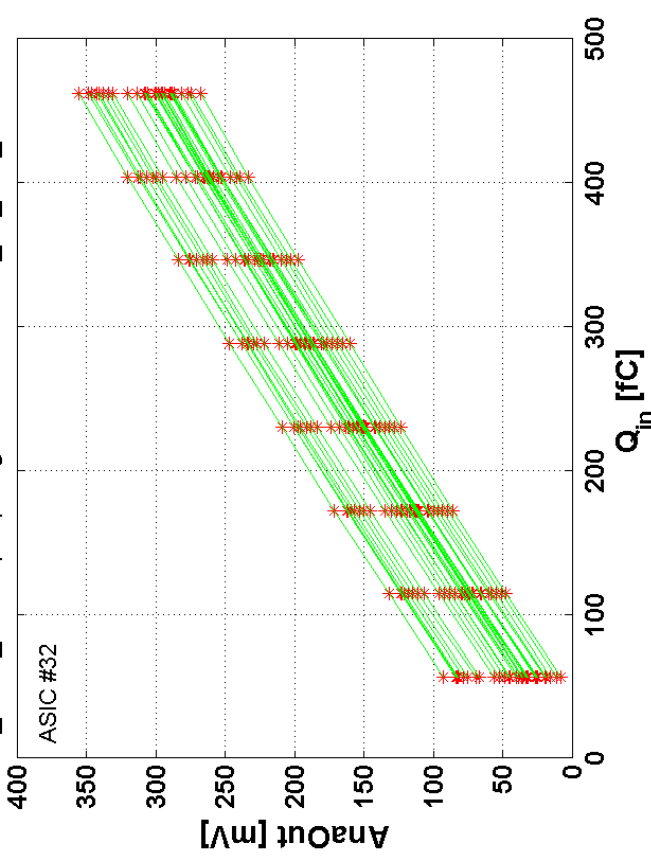
Kanał energetyczny (slow shaper)



Ana_ASIC_b-A64-pospos-gx1-vTH7-ICAL31_32_255_results.dat



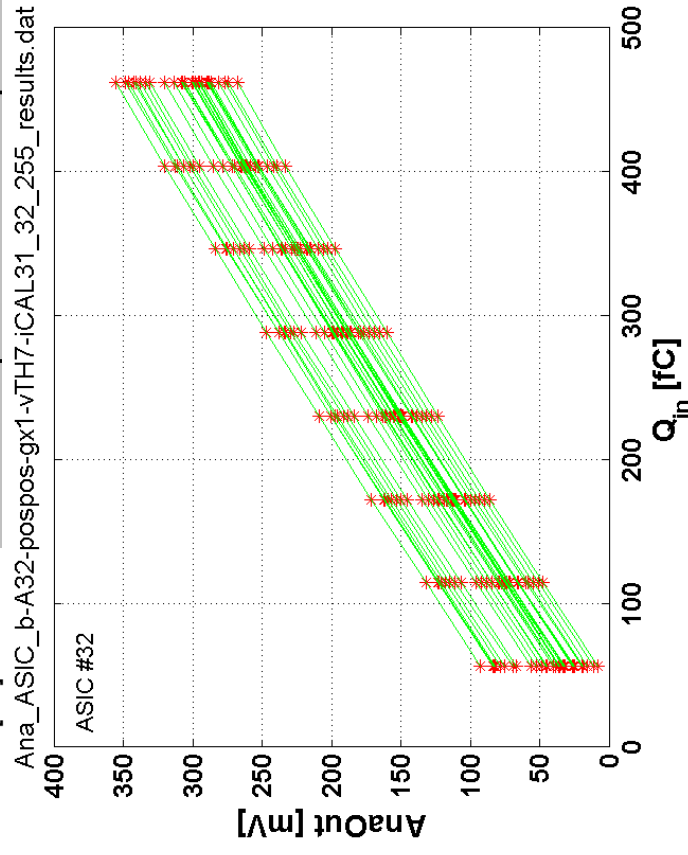
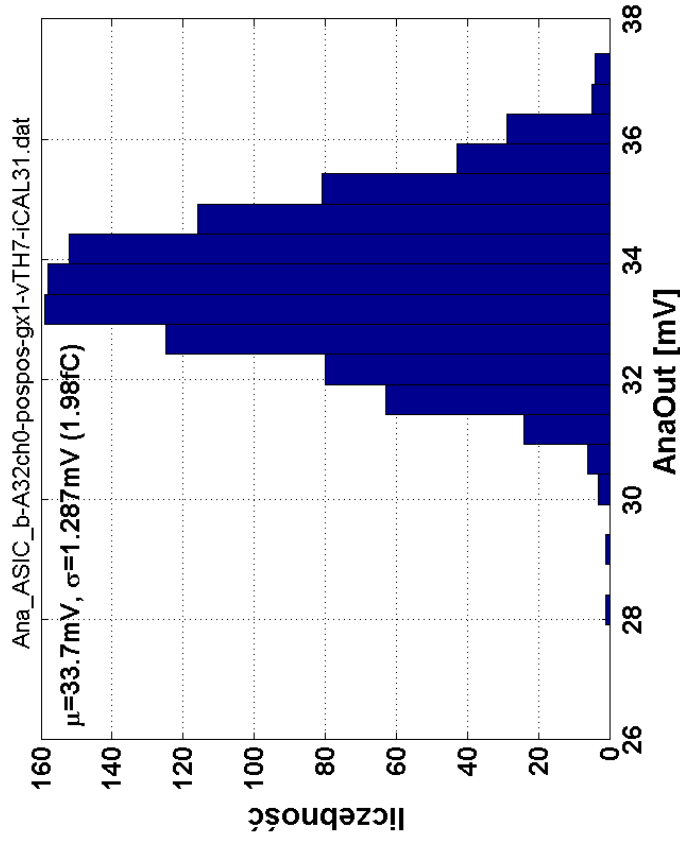
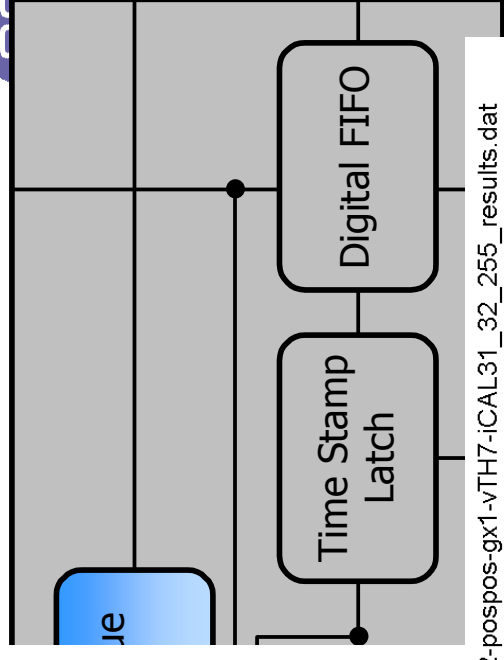
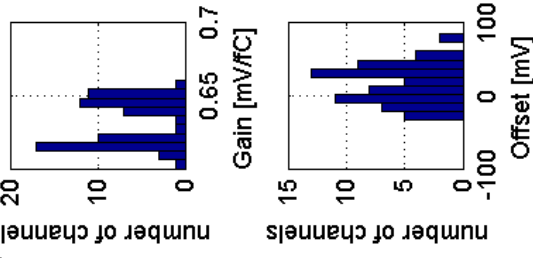
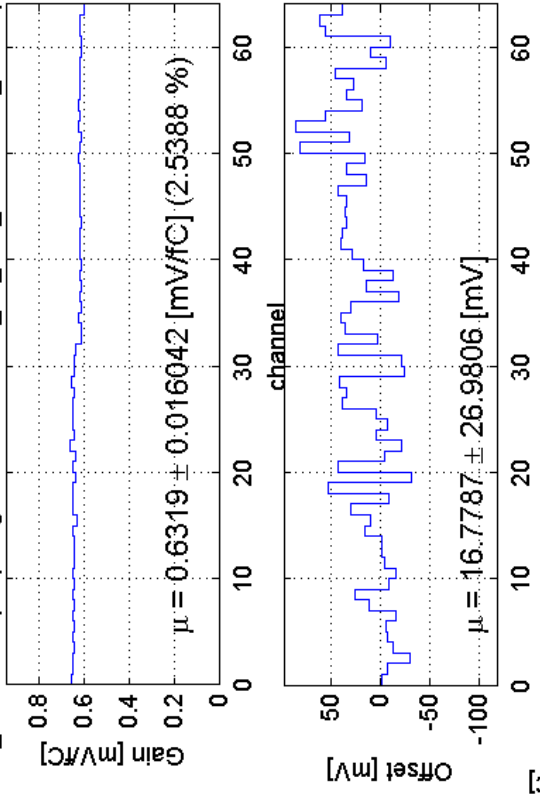
Ana_ASIC_b-A32-pospos-gx1-vTH7-ICAL31_32_255_results.dat



Kanał energetyczny (slow shaper)

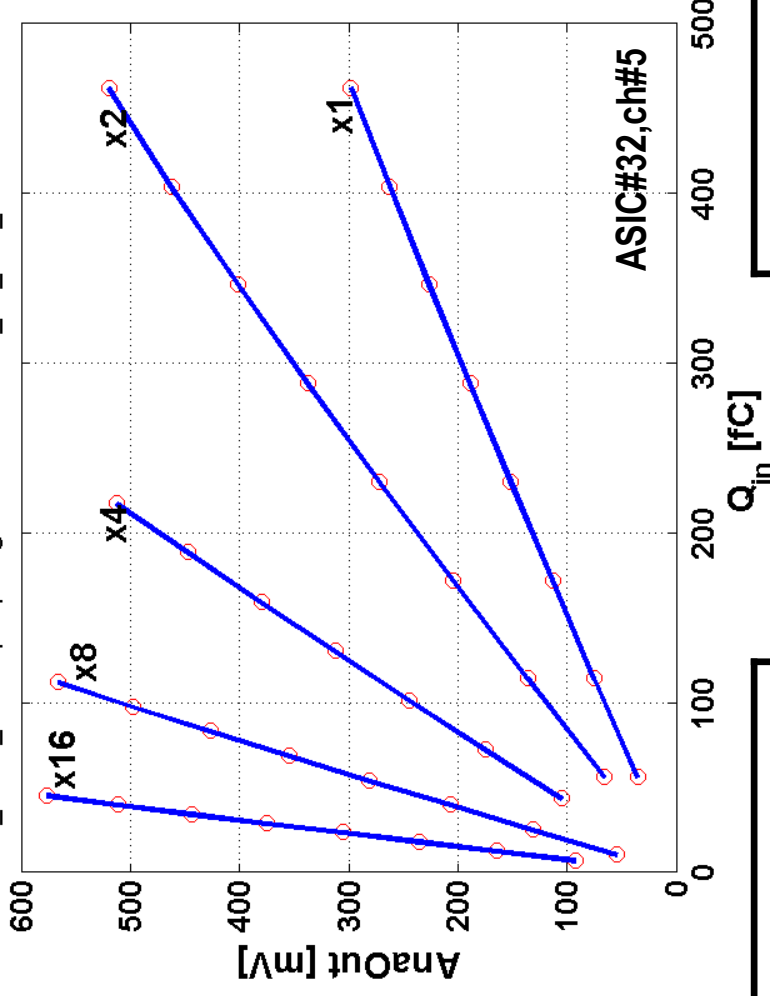


E:\Home\Wiacek\pomiar\MSGCROCv1_0\ASIC_board_1\03-01-08_AnaOut\
na_ASIC_b-A32A64-pospos-gx1-vTH7-ICAL31_32_255_results.dat_NoChip:1_FitLinear



Kanał energetyczny (slow shaper)

Ana_ASIC_b-A32-pospos-gx1-vTH7-ICAL31_32_255_results.dat-ch#5

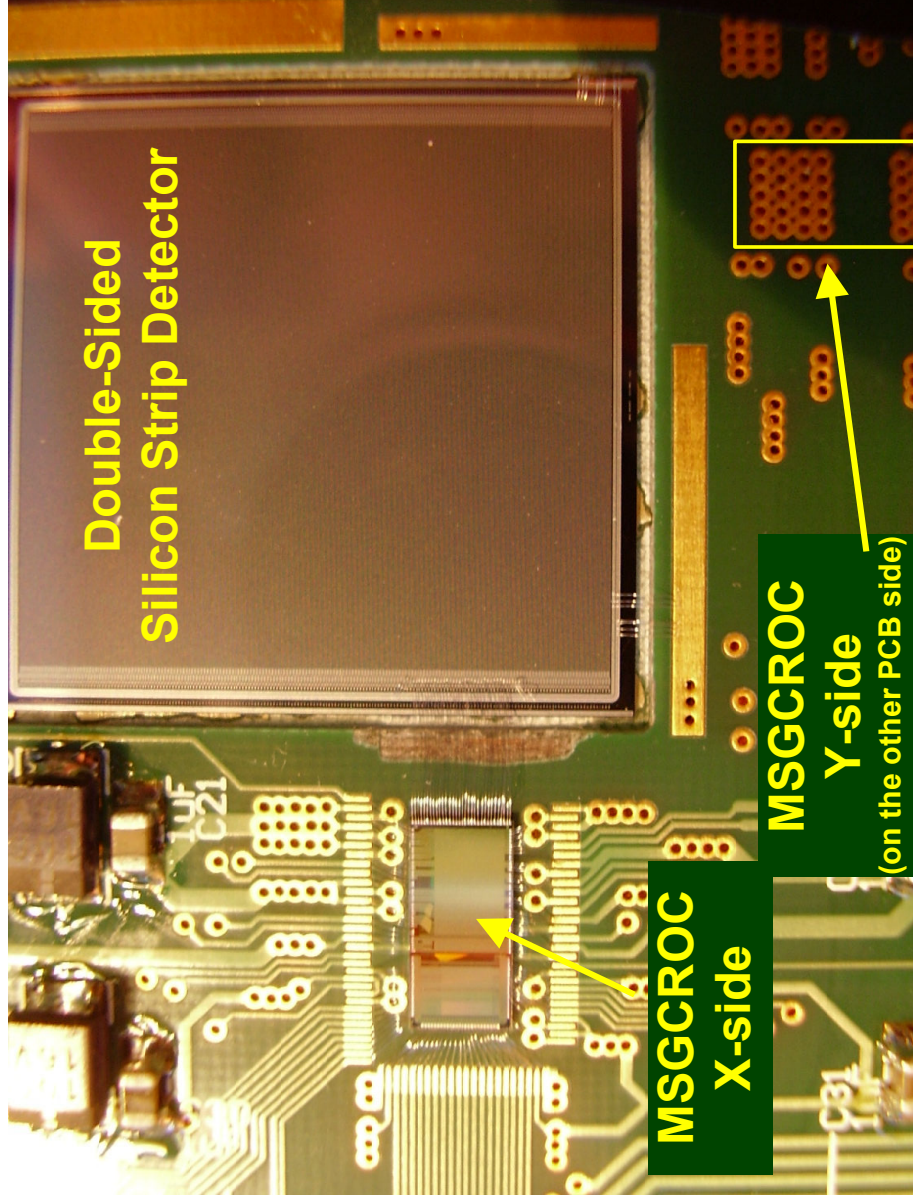


ASIC #32	
Gain [mV/fC]	Offset [mV]
0.6470 ± 0.0056 (0.9%)	3.7 ± 23.2
1.121 ± 0.011	12.1 ± 23.9
2.341 ± 0.020	7.7 ± 23.5
5.029 ± 0.052	6.8 ± 23.9
12.68 ± 0.15 (1.1%)	7.6 ± 24.7

x1
x1.7
x3.6
x7.8
x19.7

ASIC #64	
Gain [mV/fC]	Offset [mV]
0.6168 ± 0.0048 (0.8%)	29.8 ± 24.2
1.0606 ± 0.0099	39.8 ± 25.2
2.244 ± 0.016	35.4 ± 25.0
4.835 ± 0.044	35.9 ± 25.3
12.28 ± 0.11 (0.9%)	7.6 ± 24.7

Pomiary ze źródłem promieniowania



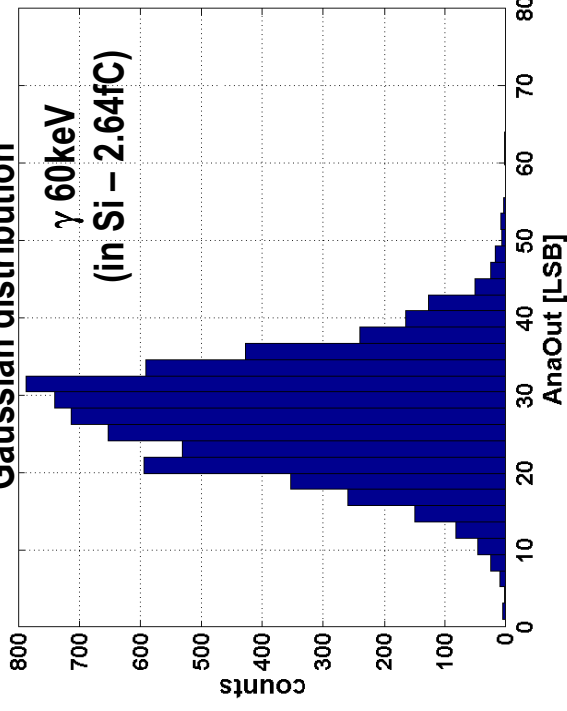
Pomiary ze źródłem promieniowania



Amplitude distribution

γ -rays ^{241}Am source

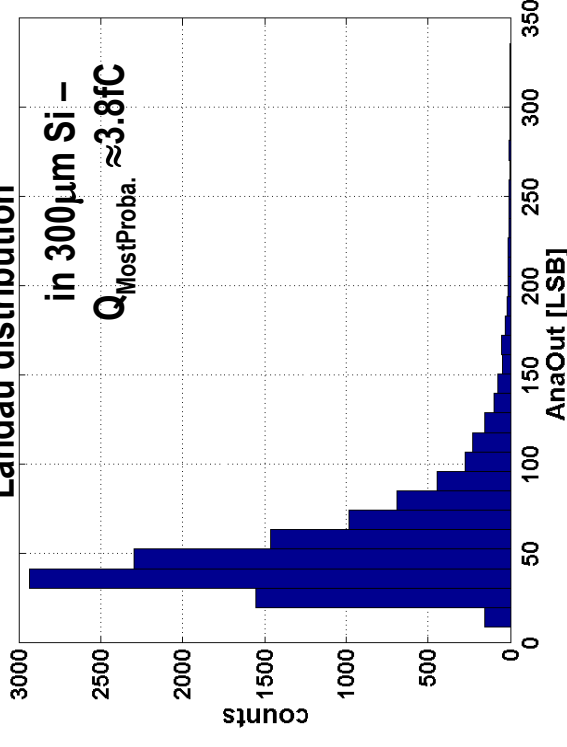
Gaussian distribution



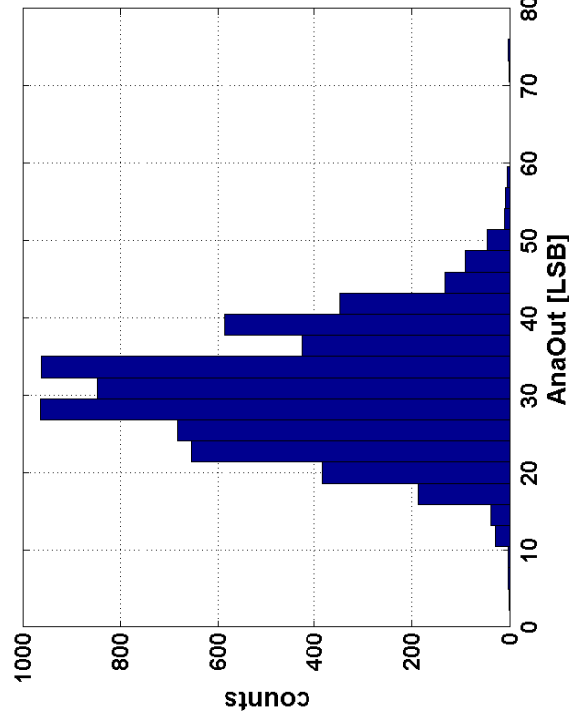
Amplitude distribution

Electrons ^{90}Sr source

Landau distribution



X-strip



Y-strip

